



Electronics Systems (938II)

Lecture 3.3

Semiconductor Memories – EPROM and EEPROM

Brief recall

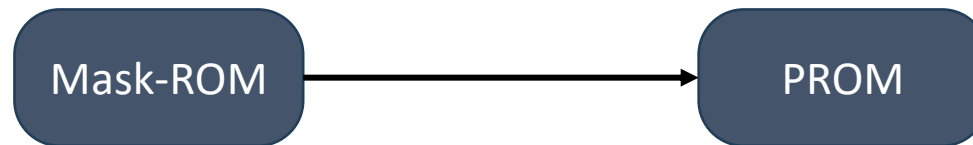
- Evolution of Read-Only Memories (ROMs)

Content of memory depends on mask

Mask-ROM

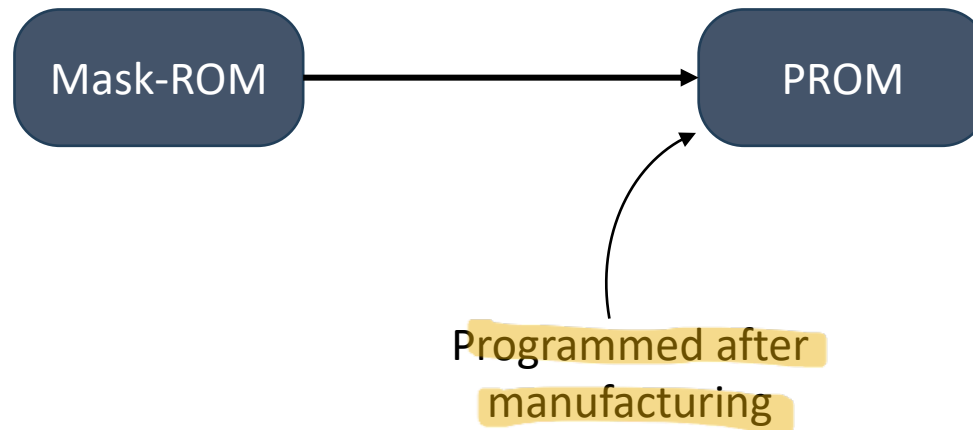
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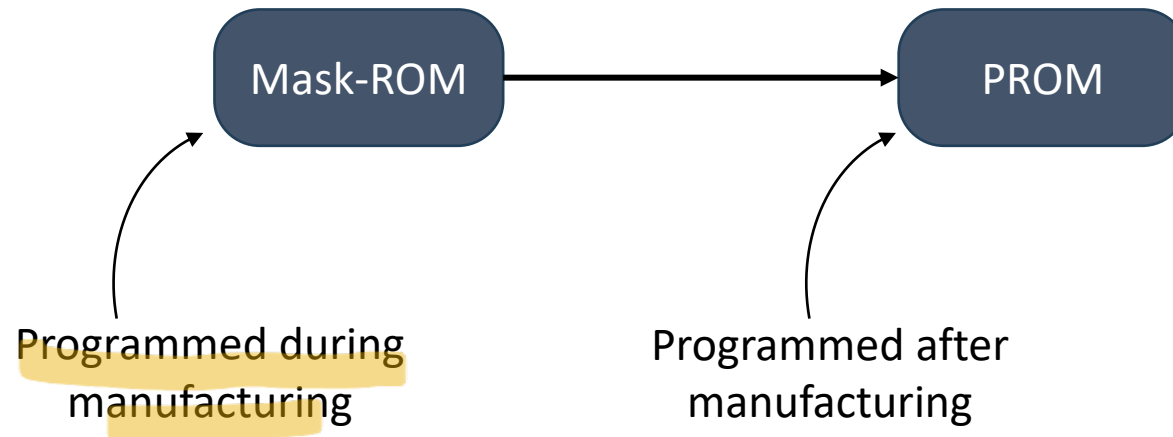
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- Evolution of Read-Only Memories (ROMs)



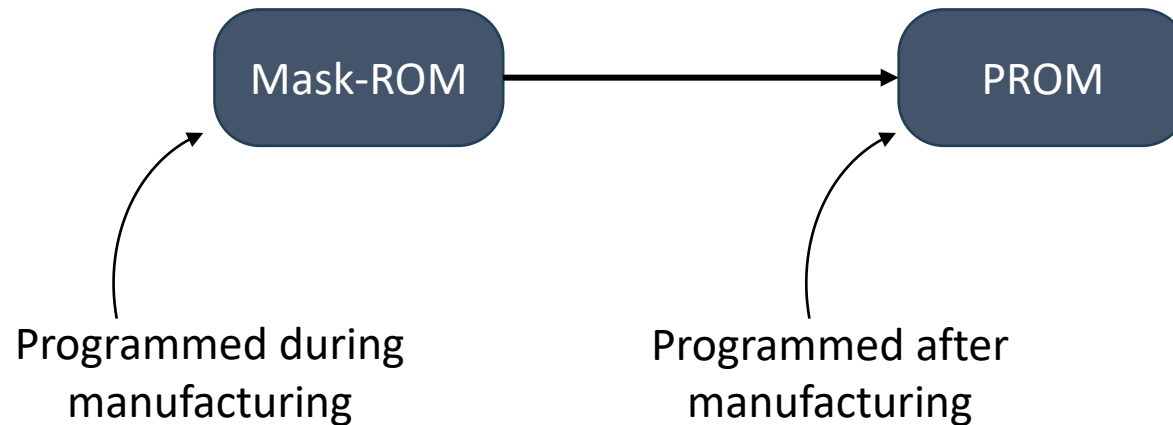
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- Evolution of Read-Only Memories (ROMs)



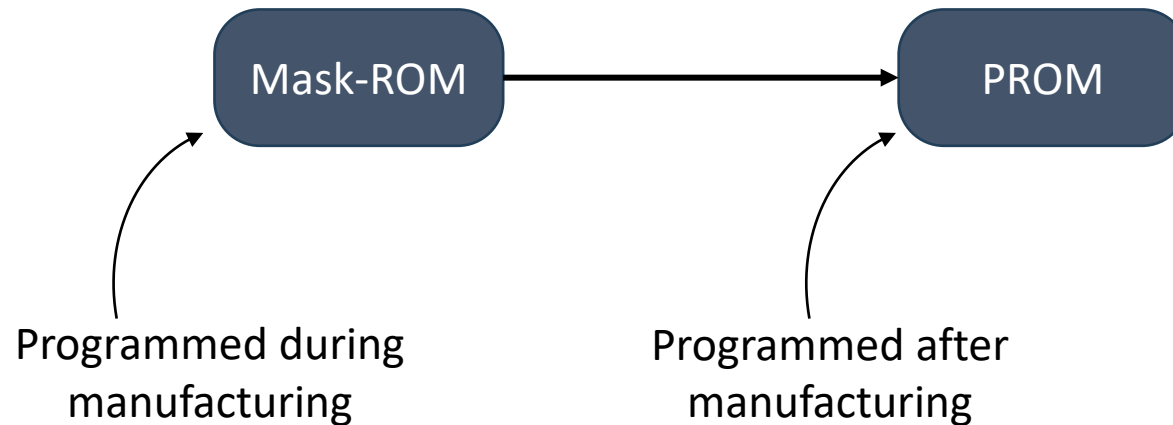
What after?

- Evolution of Read-Only Memories (ROMs)



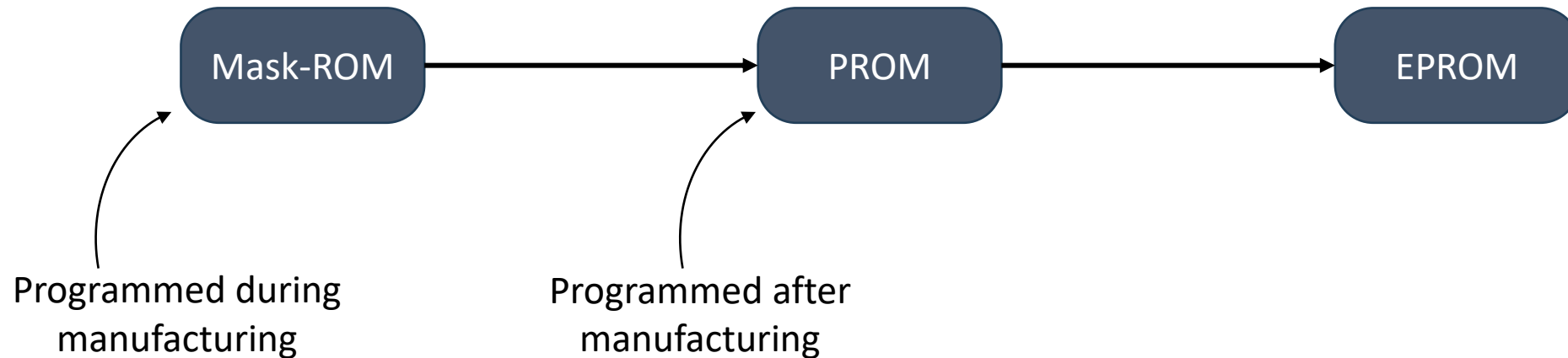
EPROM

- Evolution of Read-Only Memories (ROMs)
 - After PROM: Erasable PROM (EPROM)



EPROM

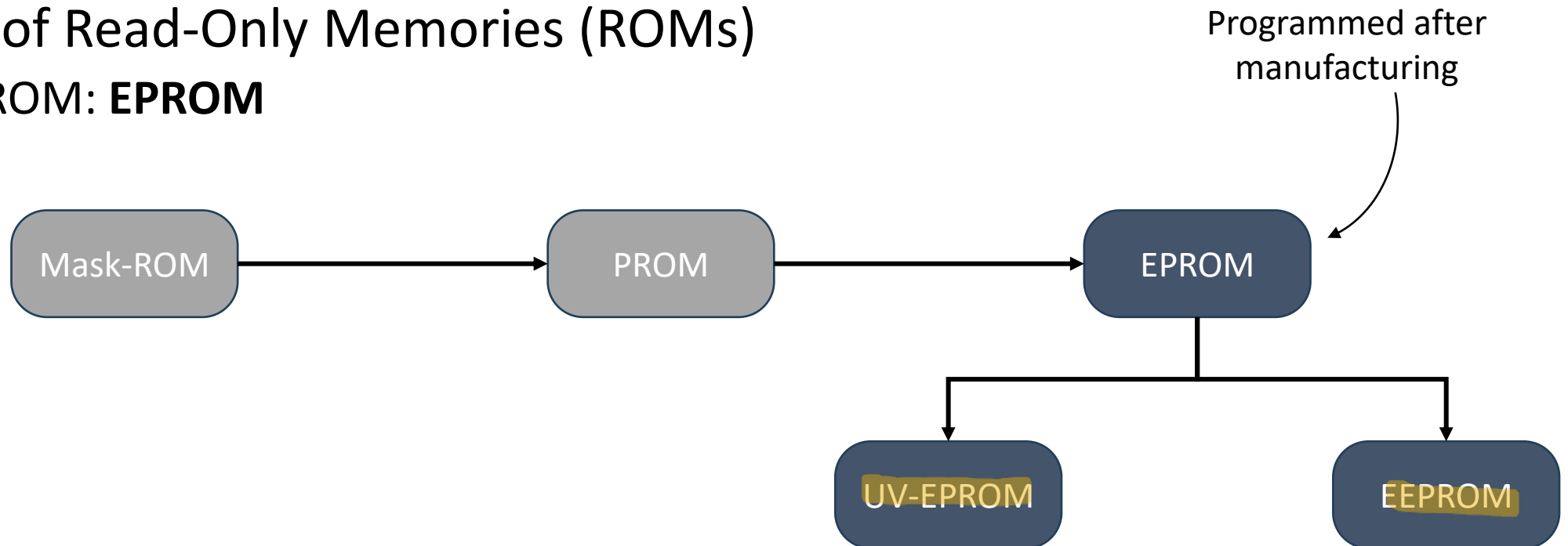
- Evolution of Read-Only Memories (ROMs)
 - After PROM: Erasable **PROM** (EPROM)



Programmable ROM in which
you can erase and rewrite memory
Programmed after
manufacturing

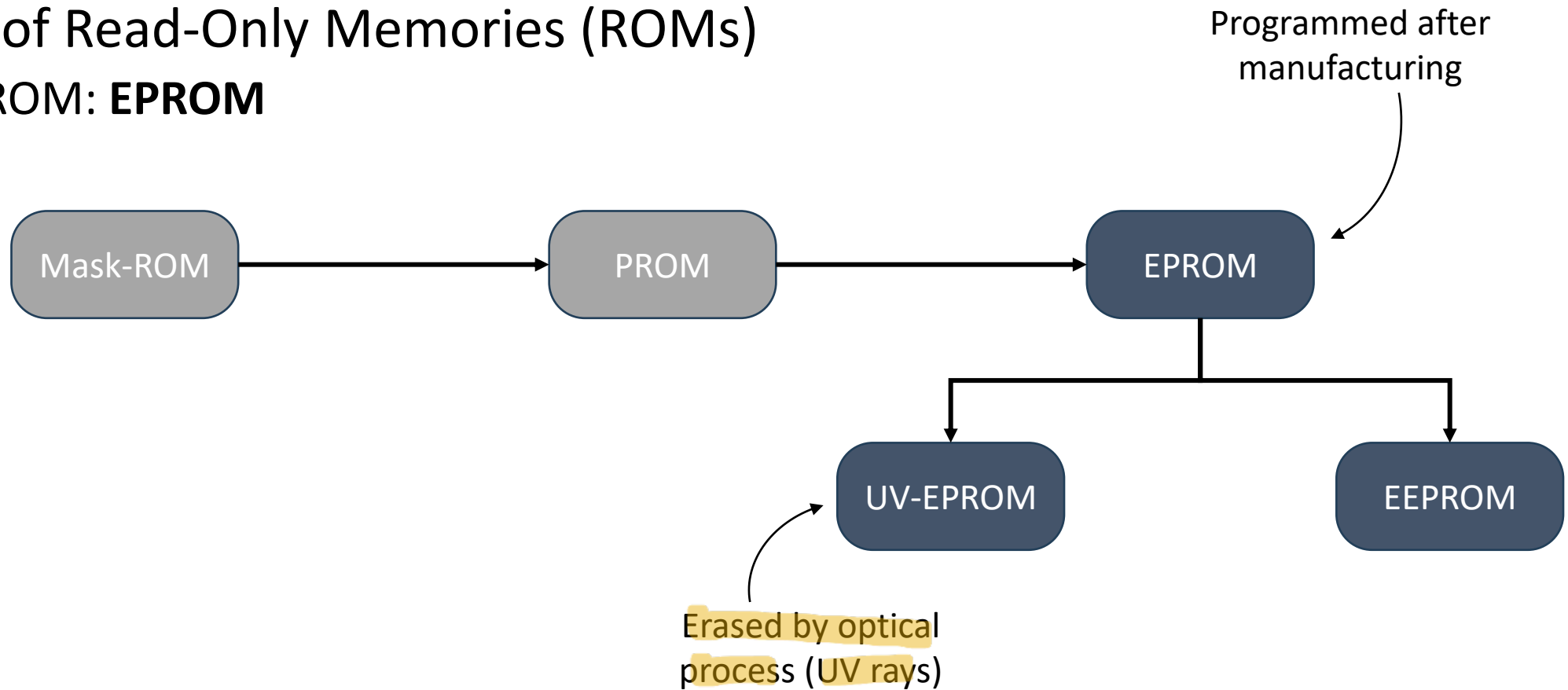
EPROM

- Evolution of Read-Only Memories (ROMs)
 - After PROM: **EPROM**



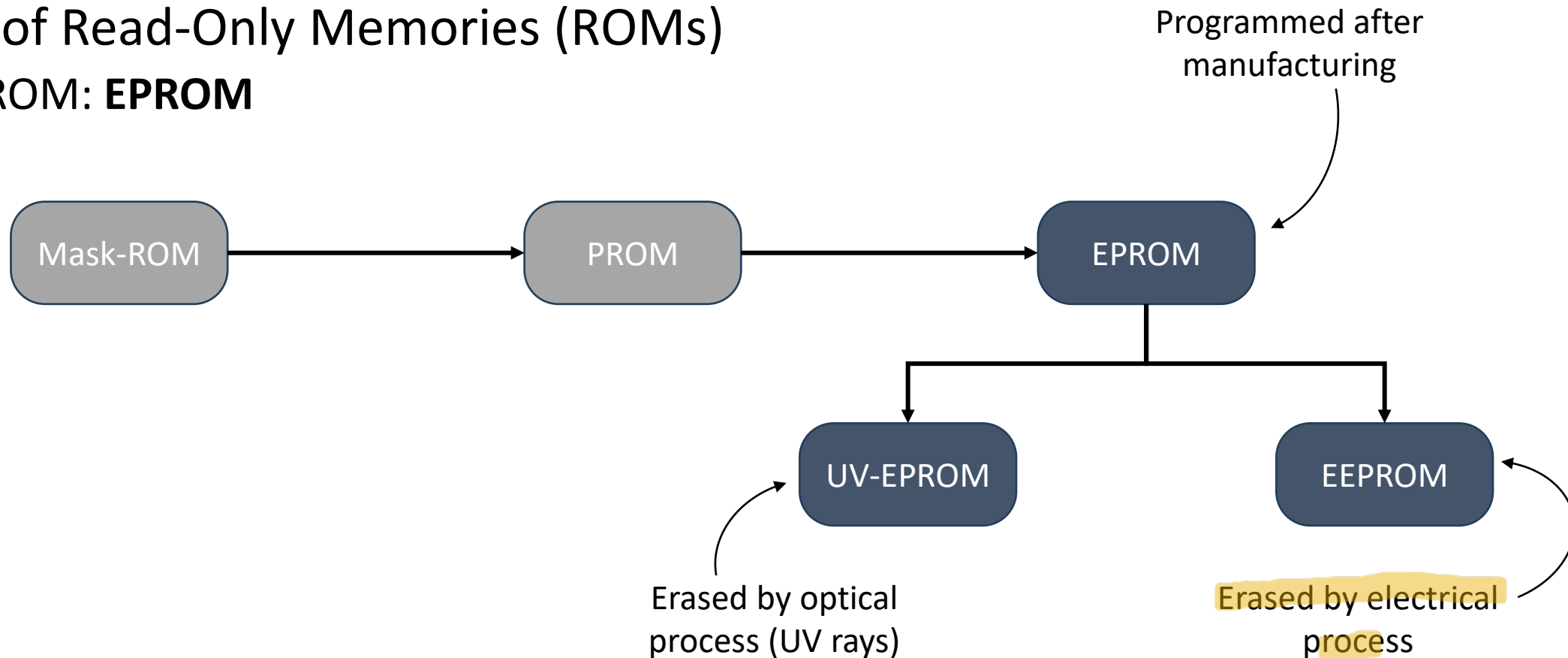
EPROM

- Evolution of Read-Only Memories (ROMs)
 - After PROM: **EPROM**



EPROM

- Evolution of Read-Only Memories (ROMs)
 - After PROM: **EPROM**



EPROM

- Generally speaking
 - It is a ROM
 - Run-time working principle similar to the that of mask-ROM/PROM
 - That can be programmed
 - And erased
 - So reprogrammed !!!

EPROM – Underlying Technology

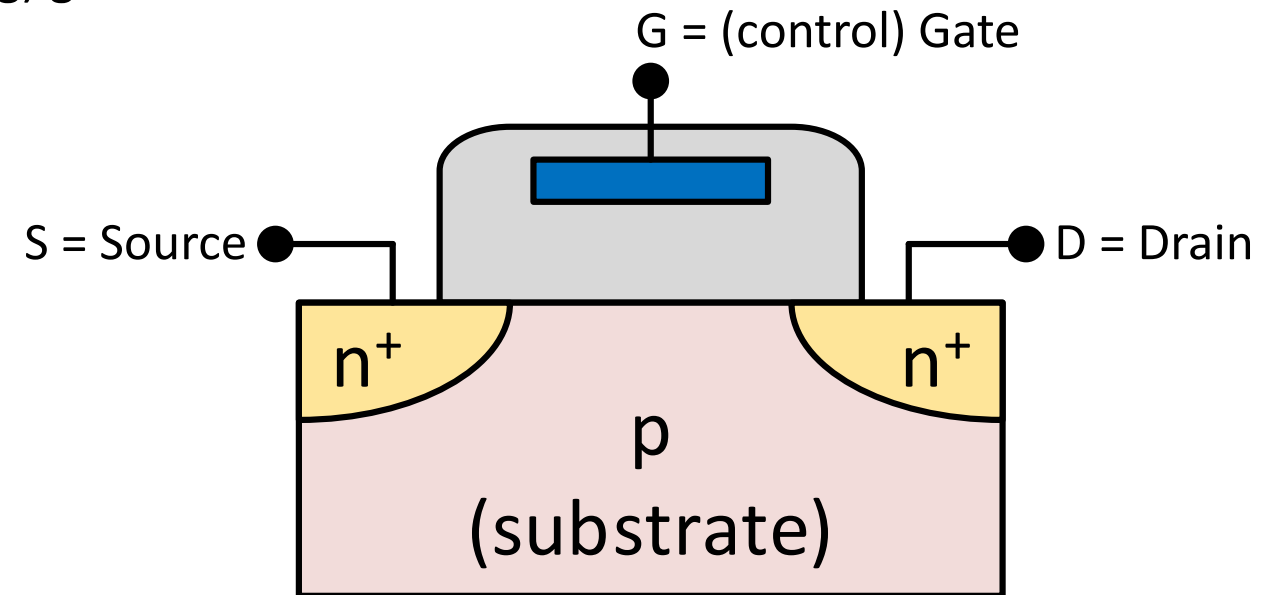
- It relies on particular MOS transistors

EPROM – Underlying Technology

- It relies on particular MOS transistors
 - **FGMOS = Floating Gate MOS**
 - In practice, a MOS + one additional (floating) gate

EPROM – Underlying Technology

- It relies on particular MOS transistors
 - **FGMOS**
 - In practice, a **MOS** + one additional (floating) gate
 - Traditional MOS transistor

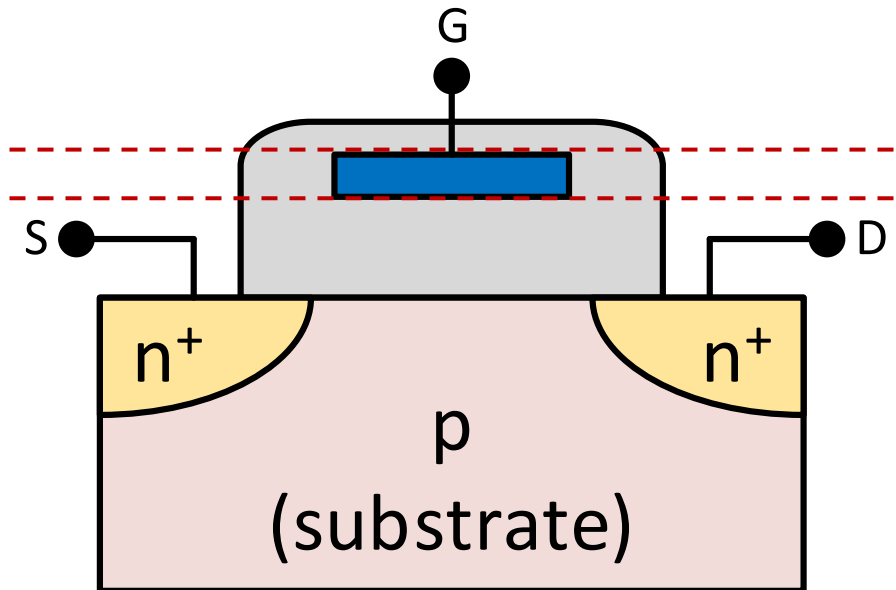


EPROM – Underlying Technology

- It relies on particular MOS transistors
 - **FGMOS**
 - In practice, a MOS + one additional (floating) gate

- Traditional **MOS** transistor

- **Metal**



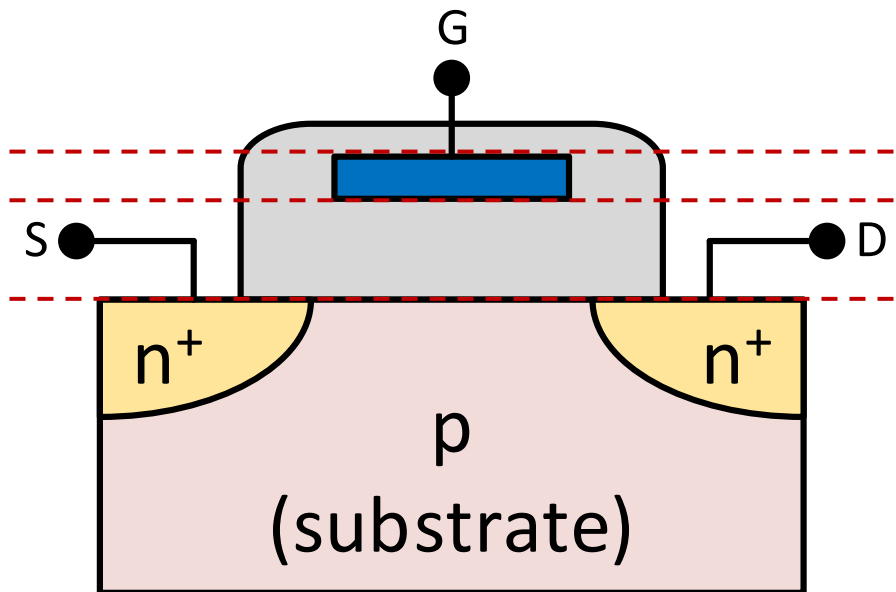
EPROM – Underlying Technology

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 - **FGMOS**
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- Traditional MOS transistor

- Metal

- Oxide



EPROM – Underlying Technology

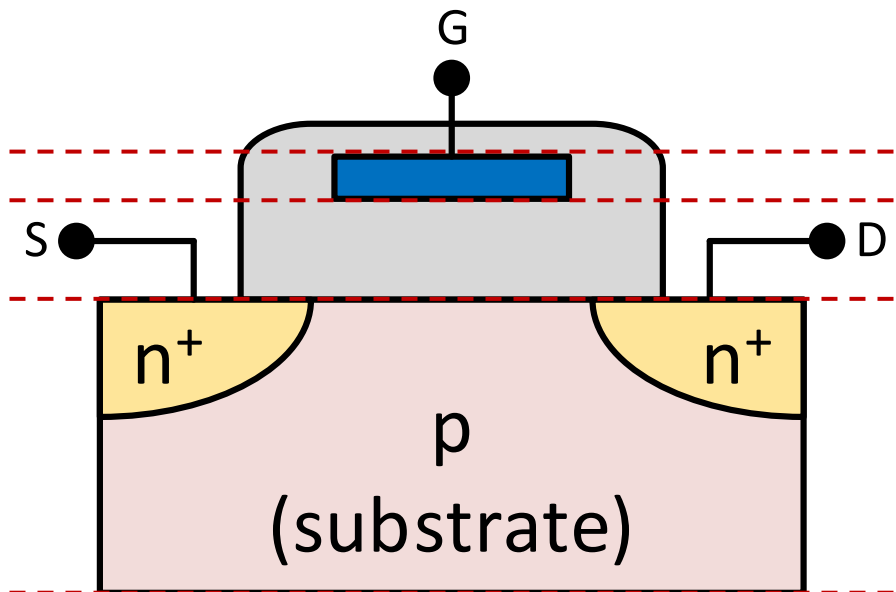
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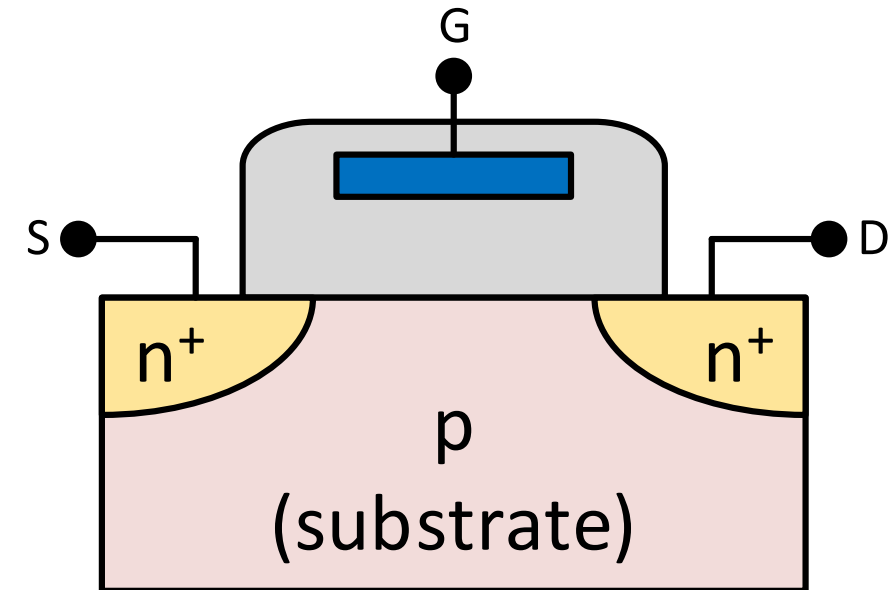
- Oxide

- Silicon



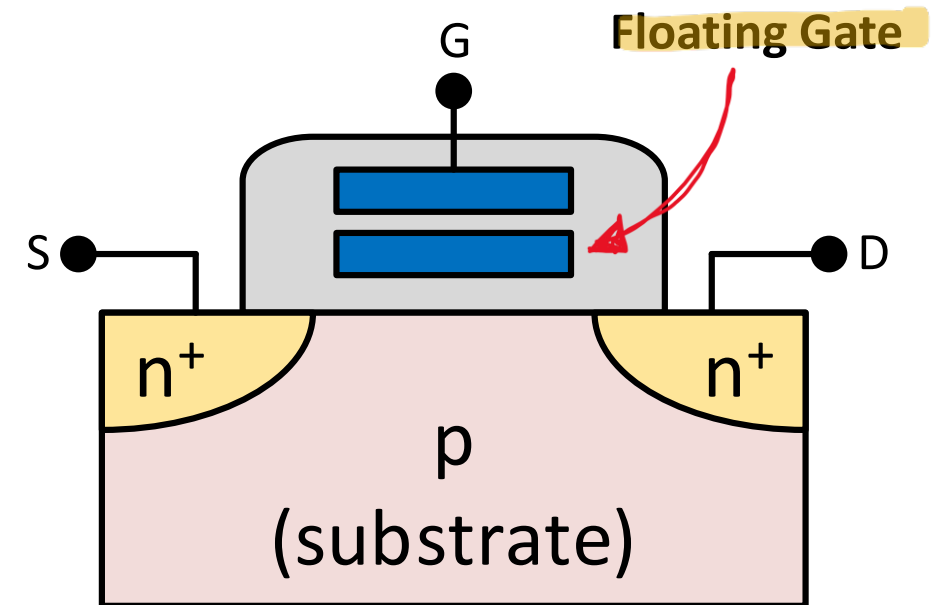
EPROM – Underlying Technology

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 - In practice, a MOS + one additional (floating) gate
 - Traditional **MOS** transistor
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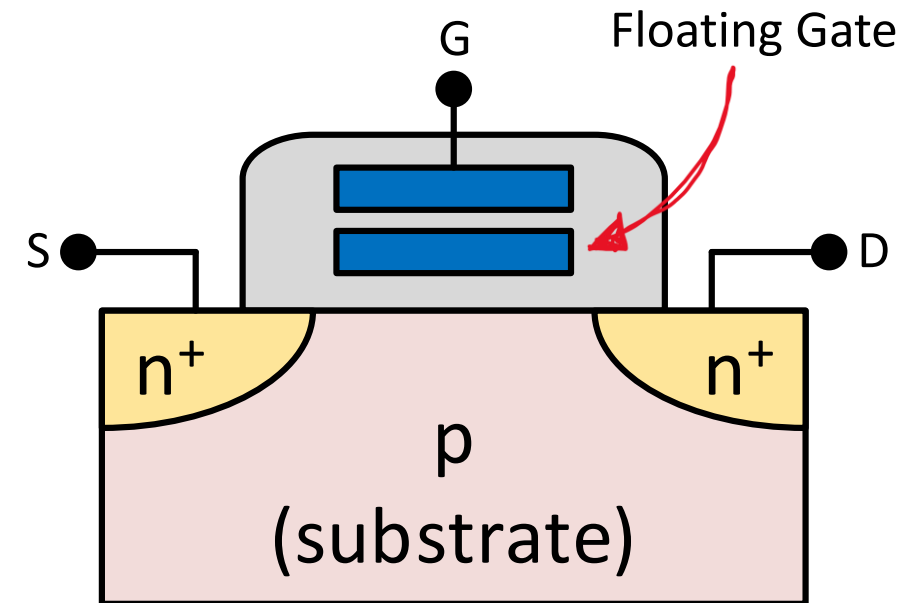
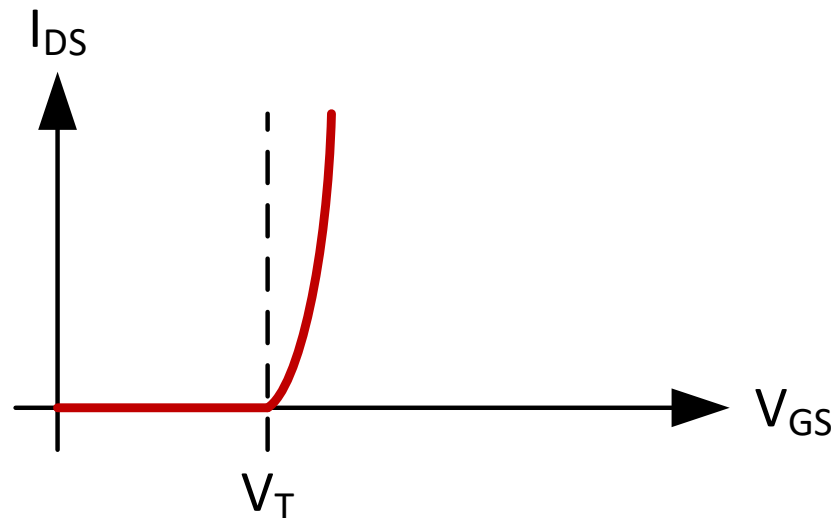
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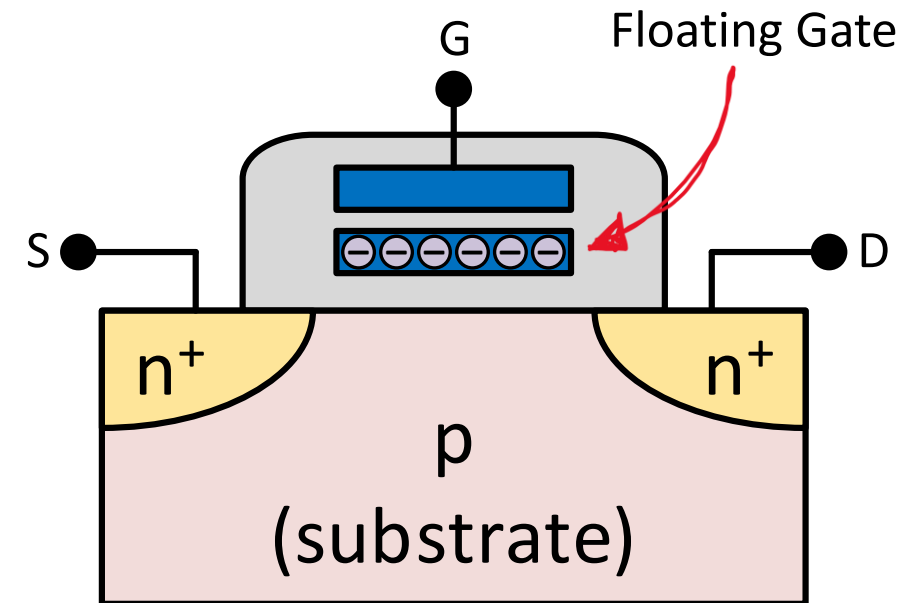
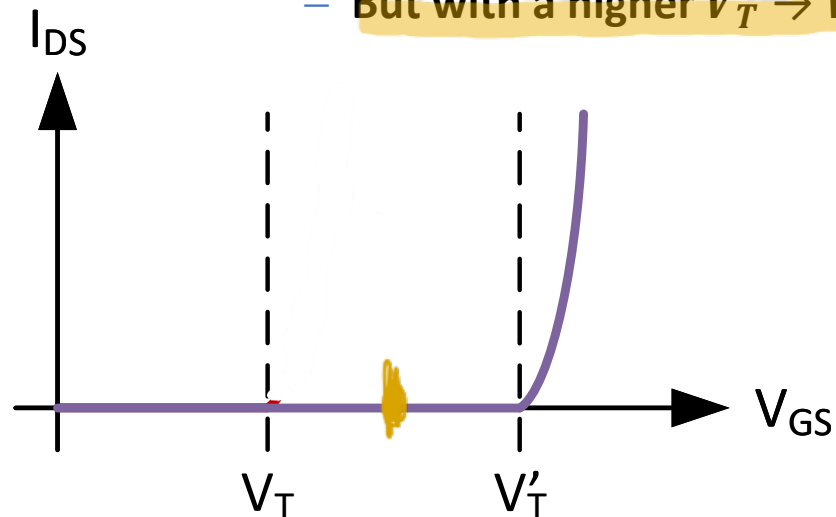
EPROM – Underlying Technology

- It relies on particular MOS transistors
 - **FGMOS**
 - In practice, a MOS + one additional (floating) gate
 - Floating gate = **empty (default)**
 - It behaves like a “traditional” MOS



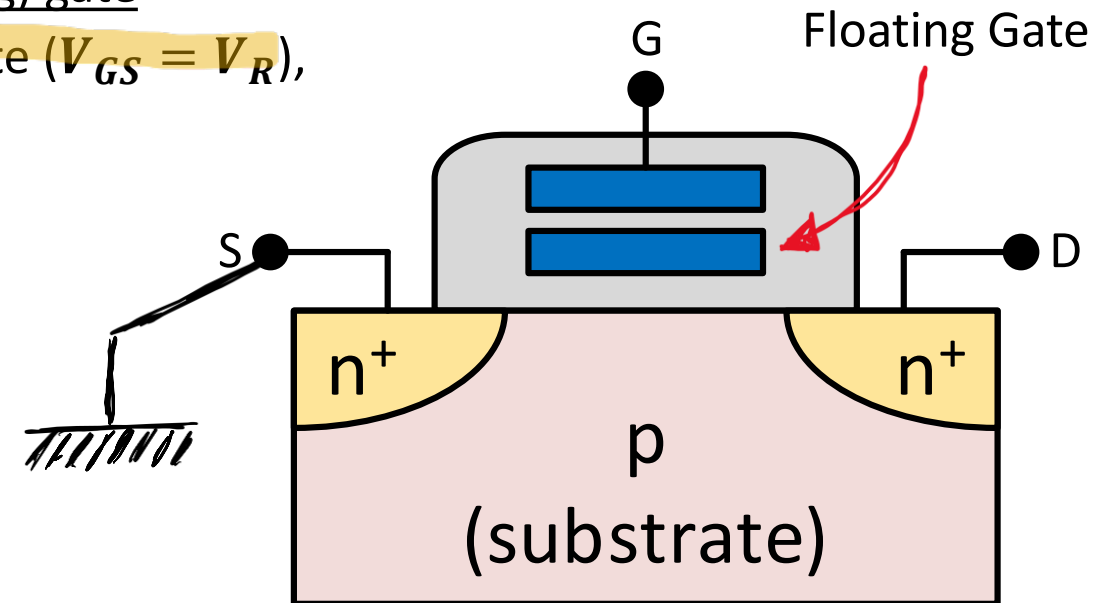
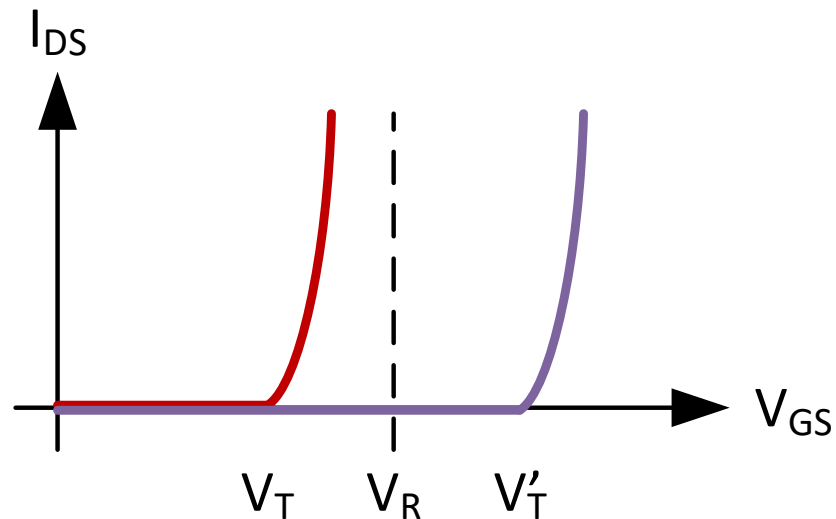
EPROM – Underlying Technology

- It relies on particular MOS transistors
 - **FGMOS**
 - In practice, a MOS + one additional (floating) gate
 - Floating gate = **full of electrons (programmed)**
 - It behaves like a “traditional” MOS
 - **But with a higher $V_T \rightarrow V'_T$**



EPROM – Underlying Technology

- It relies on particular MOS transistors
 - **FGMOS**
 - In practice, a MOS + one additional (floating) gate
 - Using a reading voltage (V_R) on the gate ($V_{GS} = V_R$), such that $V_T < V_R < V'_T$

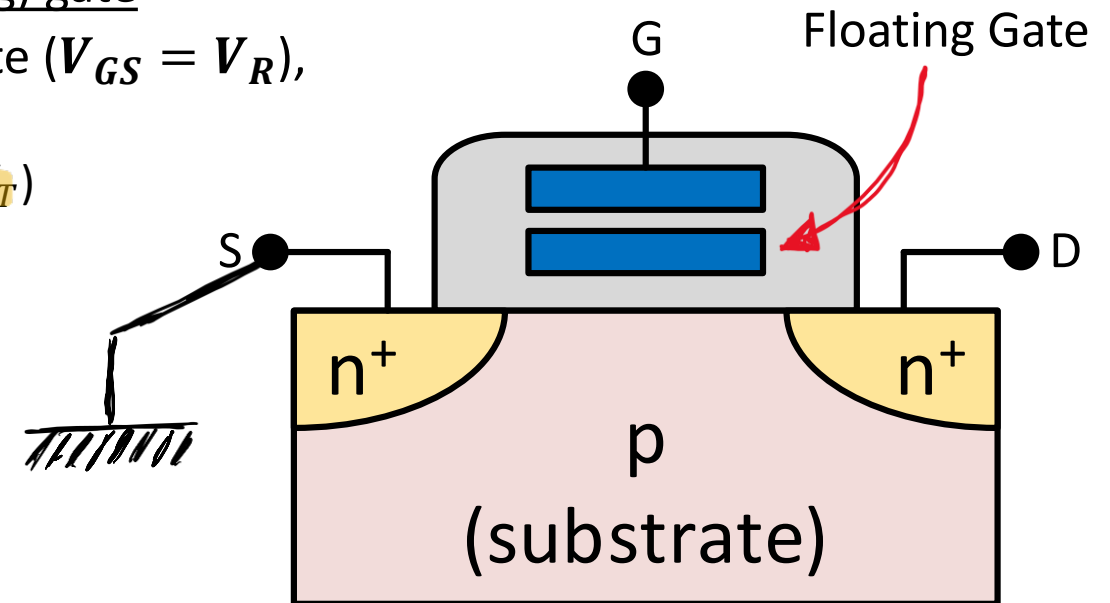
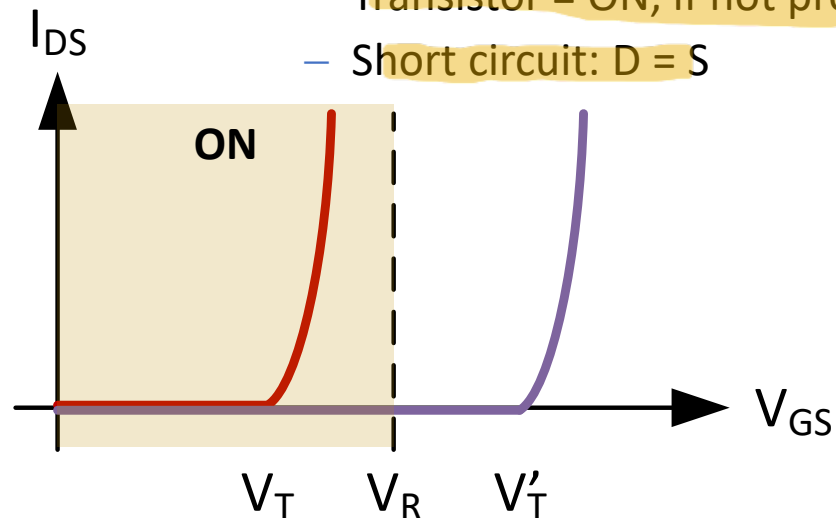


EPROM – Underlying Technology

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- **FGMOS**

- In practice, a MOS + one additional (floating) gate
 - Using a reading voltage (V_R) on the gate ($V_{GS} = V_R$), such that $V_T < V_R < V'_T$
 - Transistor = ON, if not programmed (V_T)
 - Short circuit: D = S

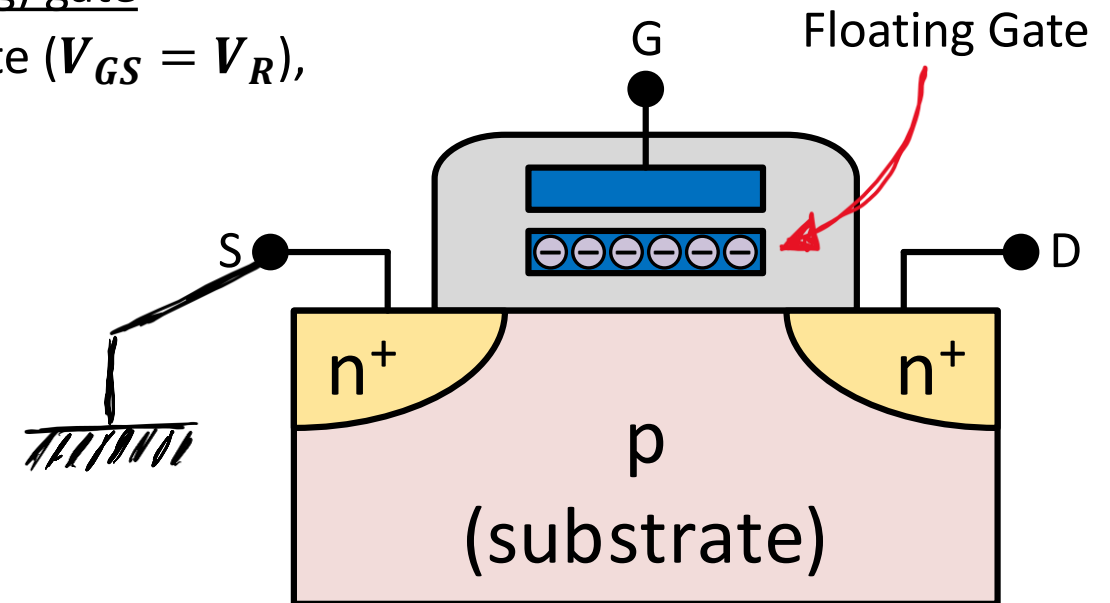
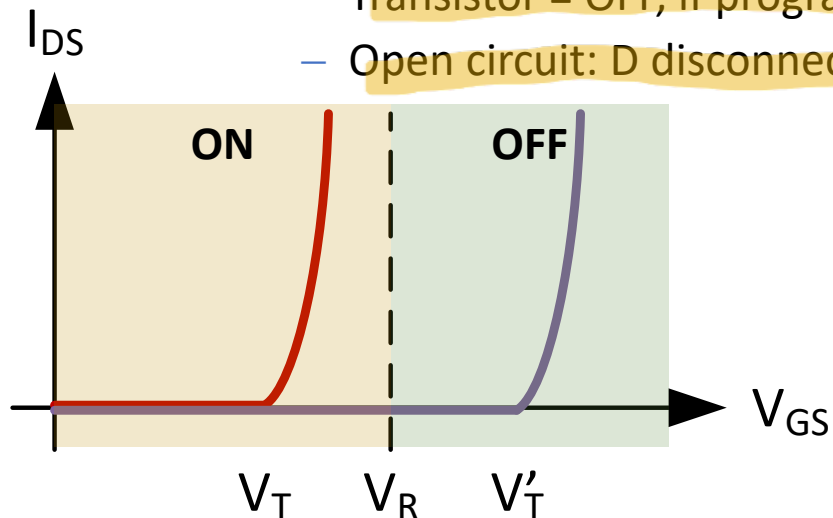


EPROM – Underlying Technology

- It relies on particular MOS transistors

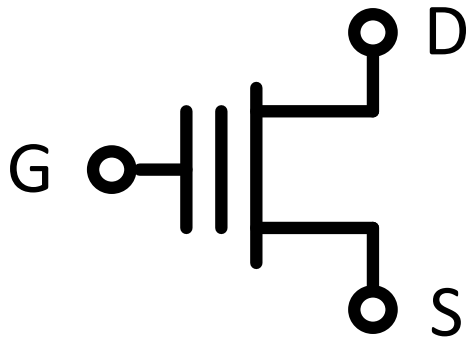
- **FGMOS**

- In practice, a MOS + one additional (floating) gate
 - Using a reading voltage (V_R) on the gate ($V_{GS} = V_R$), such that $V_T < V_R < V'_T$
 - Transistor = OFF, if programmed (V'_T)
 - Open circuit: D disconnected from S



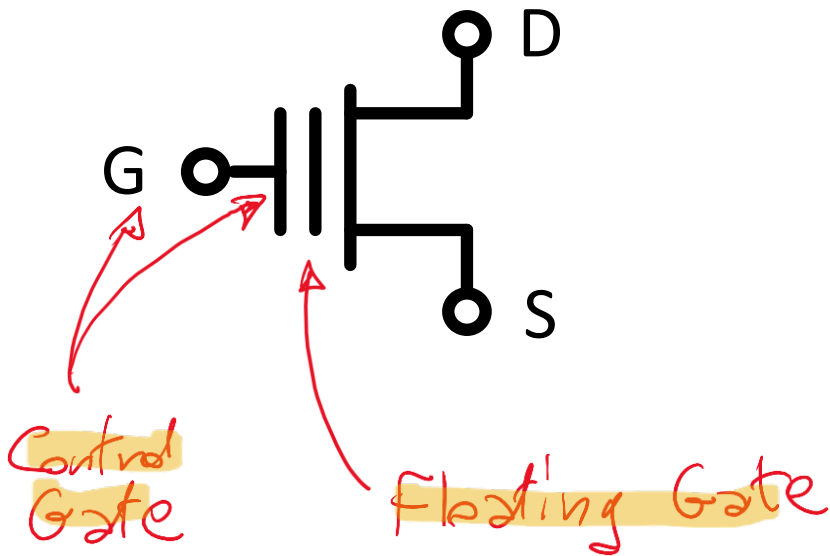
EPROM – Underlying Technology

- Applying FGMOS to semiconductor memories architecture ...
 - FGMOS symbol



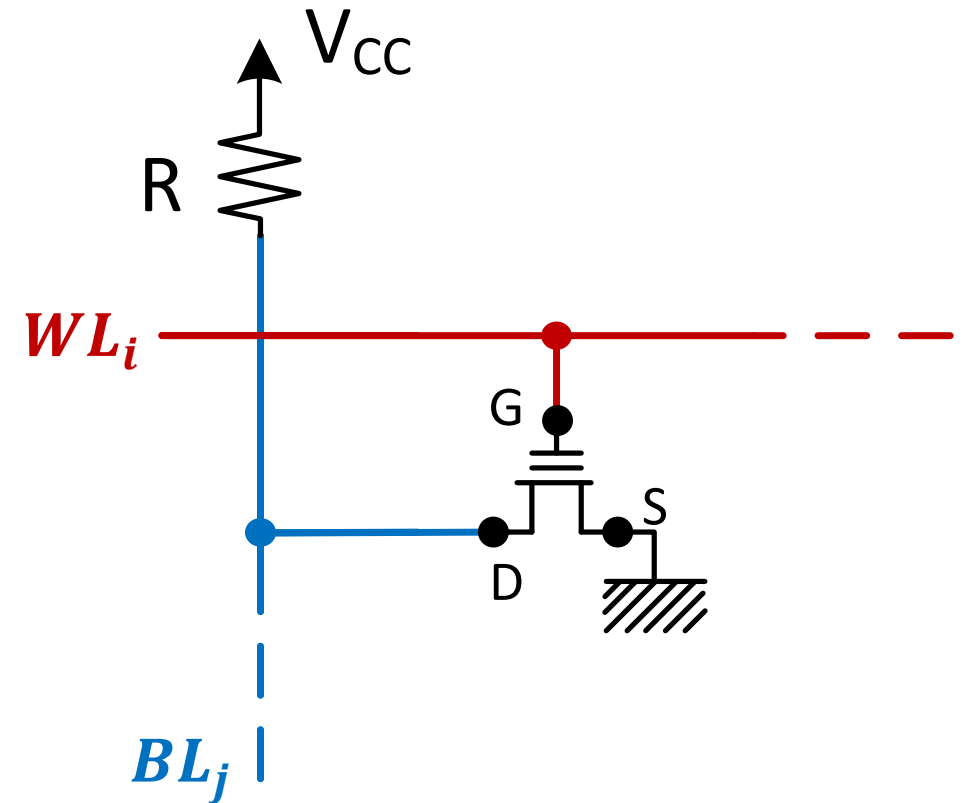
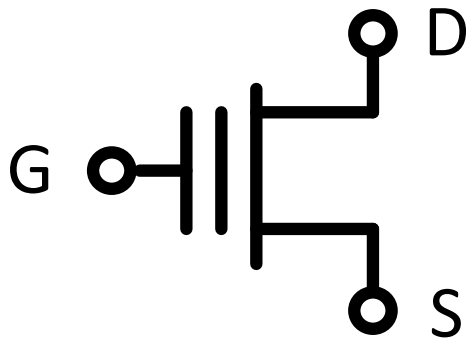
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EPROM – Underlying Technology

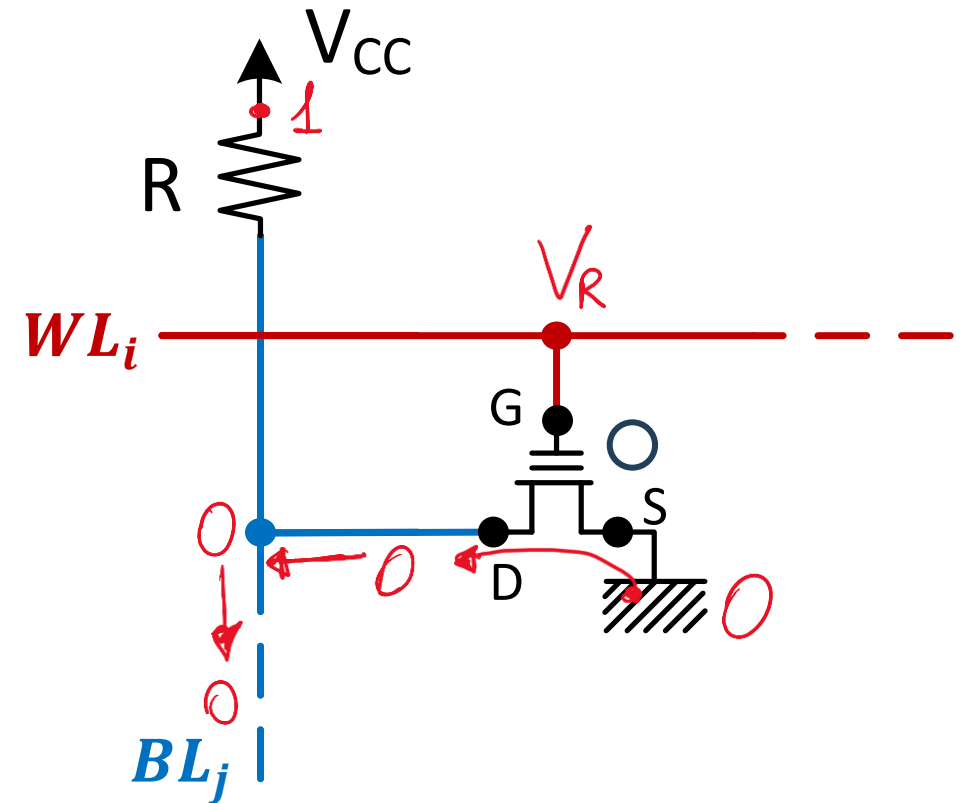
- Applying FGMOS to semiconductor memories architecture ...
 - FGMOS symbol



EPROM – Underlying Technology


- Applying FGMOS to semiconductor memories architecture ...
 - Working principle

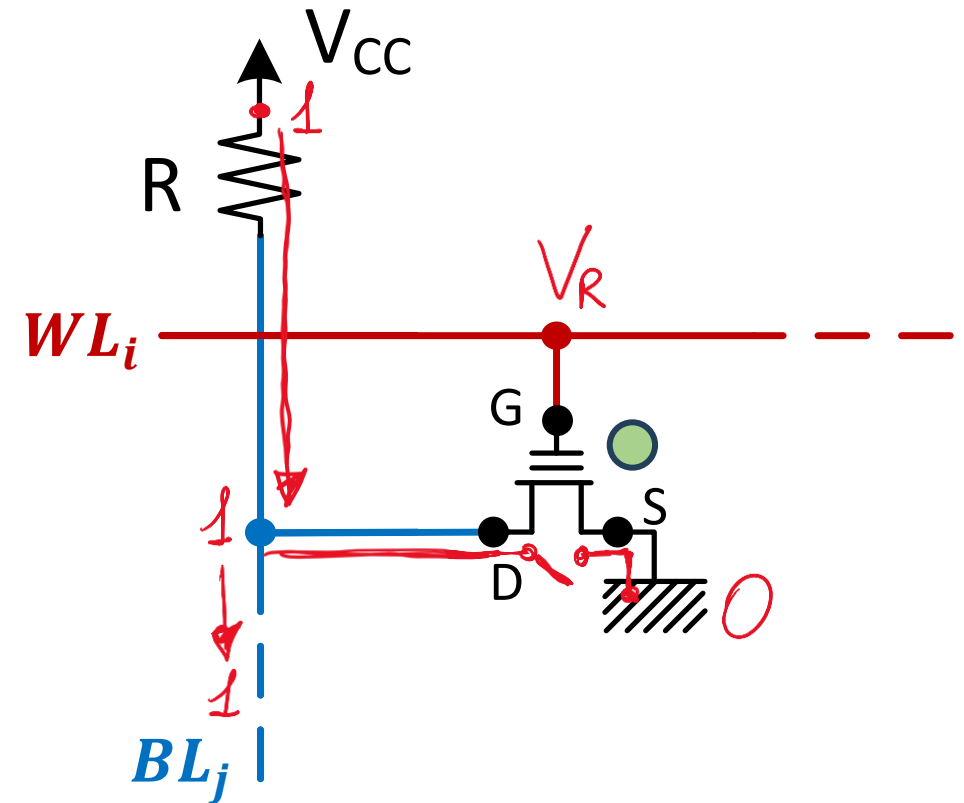
- FGMOS not programmed ○
- Reading with $V_R > V_T$ on WL_i
 - FGMOS = ON
 - FGMOS = short circuit $\rightarrow D = S \rightarrow V_D = V_S$
 - $BL_j = 0$ (logic) = V_D



EPROM – Underlying Technology

- Applying FGMOS to semiconductor memories architecture ...
 - Working principle

- FGMOS programmed 
- Reading with $V_R < V'_T$ on WL_i
 - FGMOS = OFF
 - FGMOS = open circuit $\rightarrow D \neq S \rightarrow V_D \neq V_S$
 - $BL_j = 1$ (logic) from pull-up resistor (R)



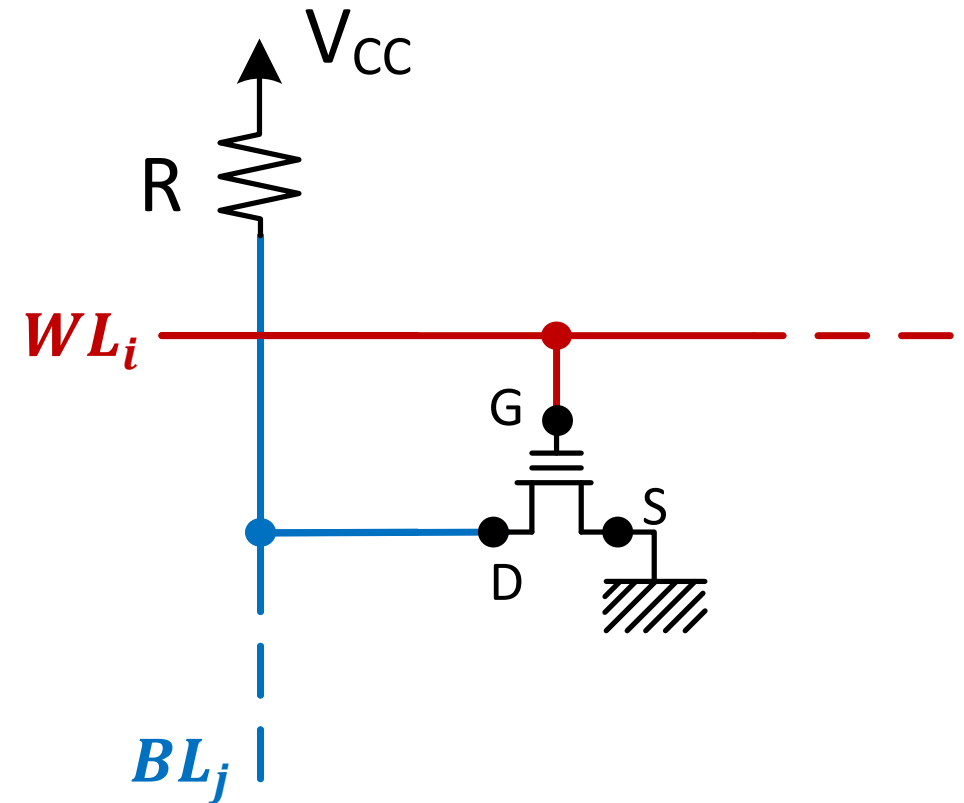
EPROM – Underlying Technology

- Applying FGMOS to semiconductor memories architecture ...

- Why does this work?

- Because of ...

1. Time required for programming/erasing
2. Data retention
3. Endurance



EPROM – Underlying Technology

- Applying FGMOS to semiconductor memories architecture ...

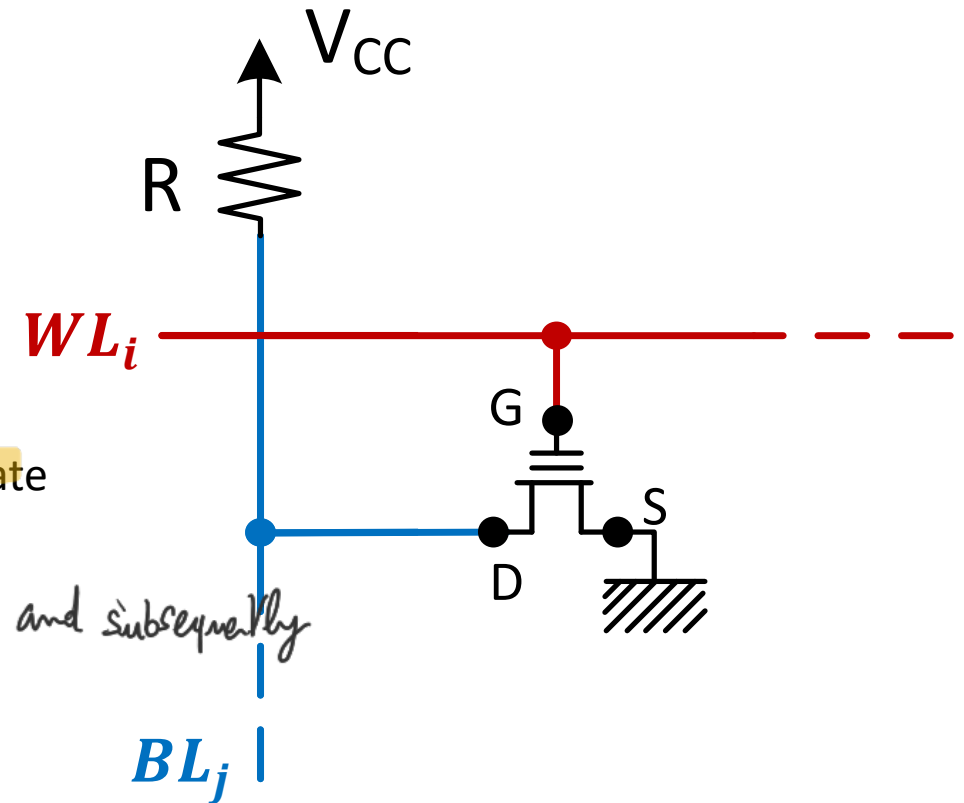
- Why does this work?

- Because of ...

1. Time required for programming/erasing

- Programming = injection of electrons into the floating gate
- Erasing = removal of electrons from the floating gate

- Erasing + programming (cycle) takes a time in the order of minutes
- process of erasing and subsequently programming*
for all transistors.



EPROM – Underlying Technology

- Applying FGMOS to semiconductor memories architecture ...

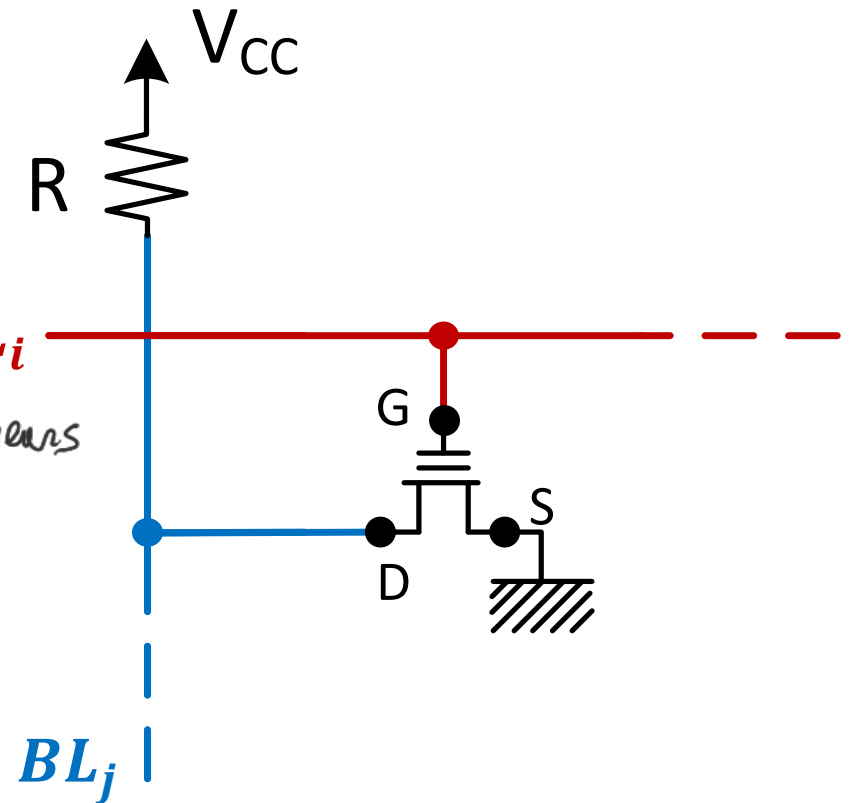
- Why does this work?

- Because of ...

2. Data retention

- Permanence time of electrons in the floating gate (once injected) $\approx 10 \div 20$ years
- Greater than duration of typical electronic application

if no additional stimuli after the programming, retention is 10-20 years



EPROM – Underlying Technology

- Applying FGMOS to semiconductor memories architecture ...
 - Why does this work?

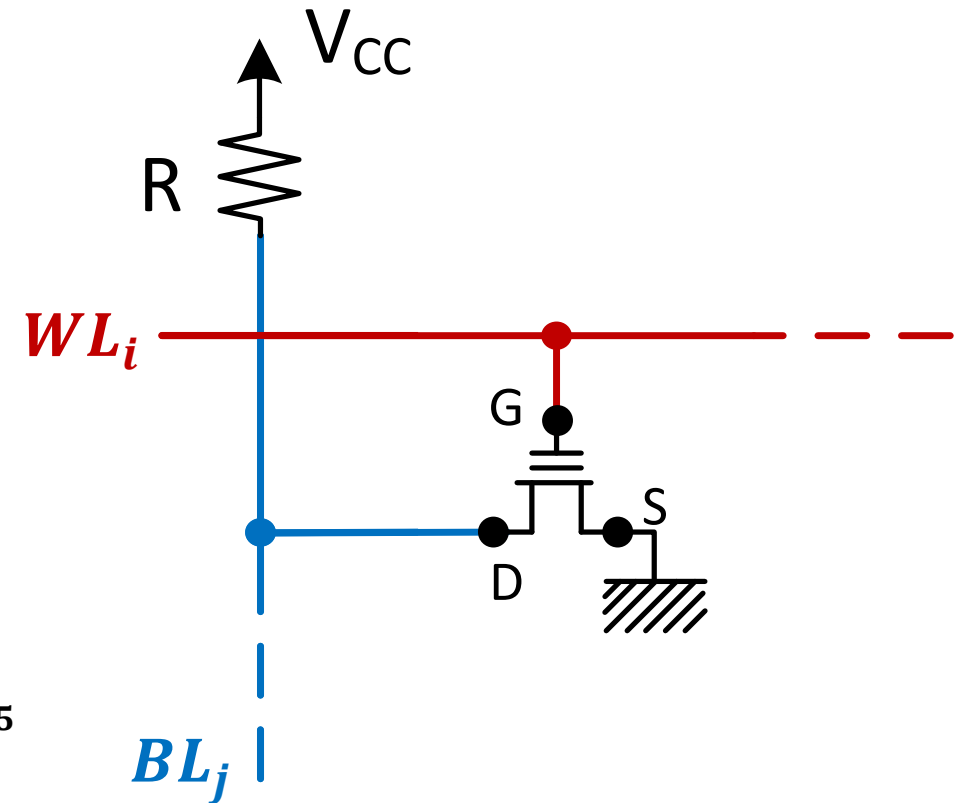
- Because of ...

3. Endurance *Resistenza*

- Number of cycles (erasing + programming) = endurance
- Endurance is limited
 - Moving electrons through the oxide degrades it

- However, it is not low: typically, in the range $10^3 \div 10^5$

oxide is broken from time to time

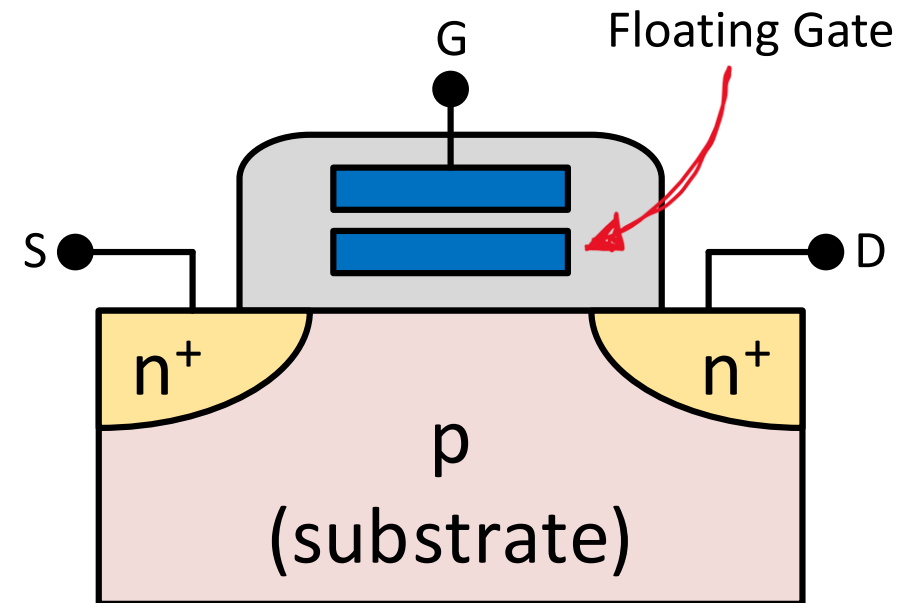
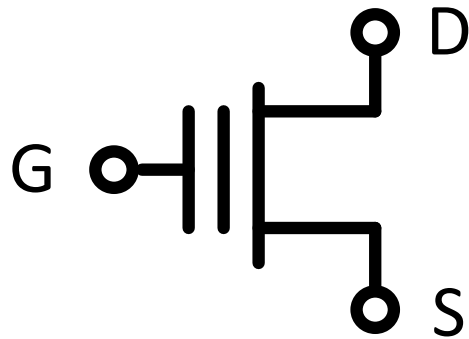


EPROM – Underlying Technology

- Two different kinds of FGMOS
 - Changing the way electrons are injected into (programming) and removed from (erasing) floating gate
 - 1. **FAMOS** = Floating-gate Avalanche-injection MOS
 - 2. **FLOTOX** = Floating-gate Tunnel-Oxide MOS
- ↑ method for injection of electrons*

FAMOS transistor

- Same layout and symbol as FGMOS
 - It was the first FGMOS



FAMOS transistor

- Working principle

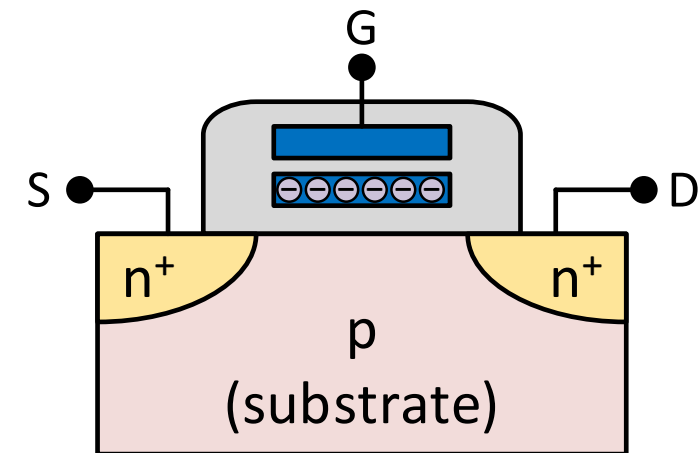
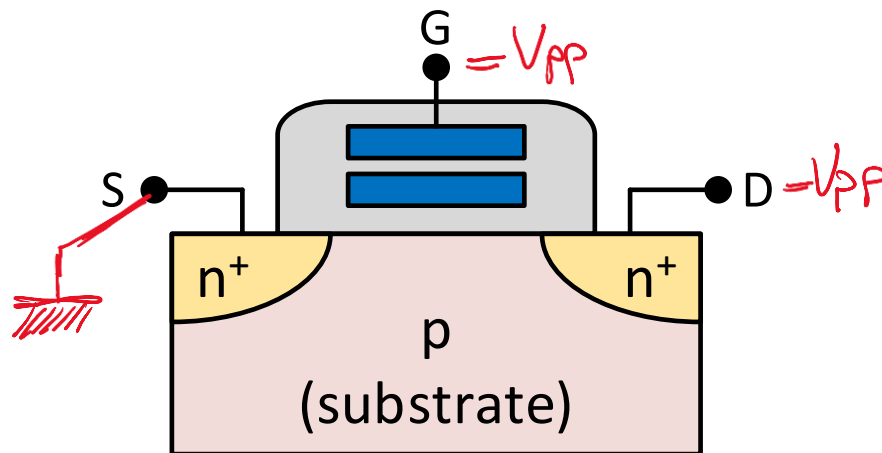
- Electrons injection (programming)

- Avalanche effect = very high current → Floating-gate Avalanche-injection MOS

- $V_G = V_D = V_{PP}$ (programming voltage, $V_{PP} \gg V_R$)

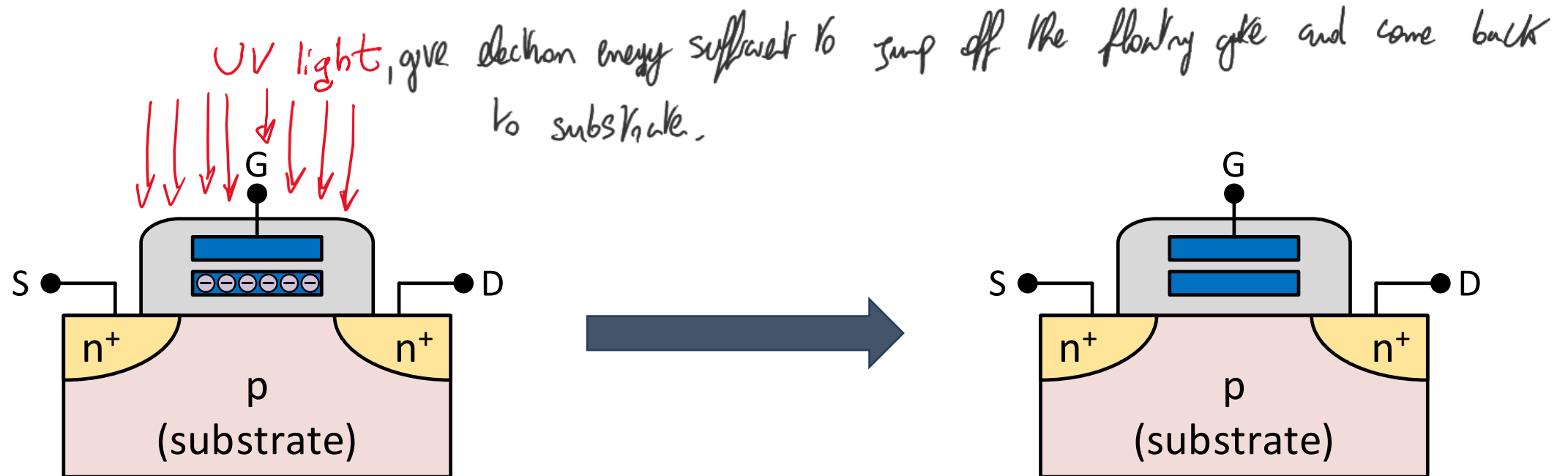
- $V_S = 0$

↑ apply a very high current to the MOS.
High probability that electrons in the channel jump inside the floating gate.
↓ Very high number of electrons



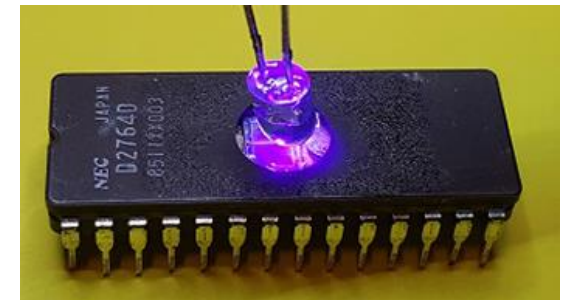
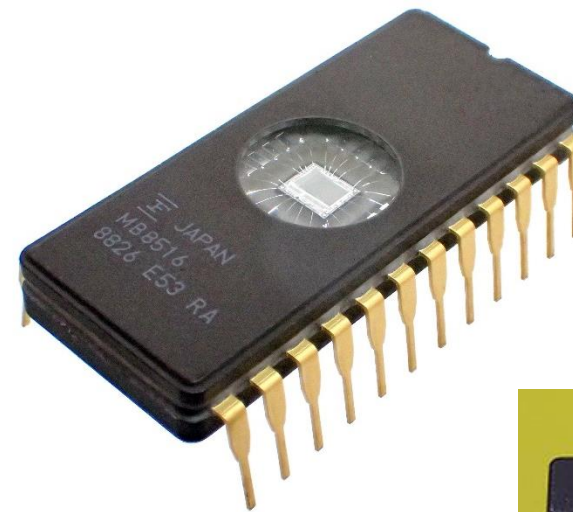
FAMOS transistor

- Working principle
 - Electrons removal (erasing)
 - Exposure to UV light



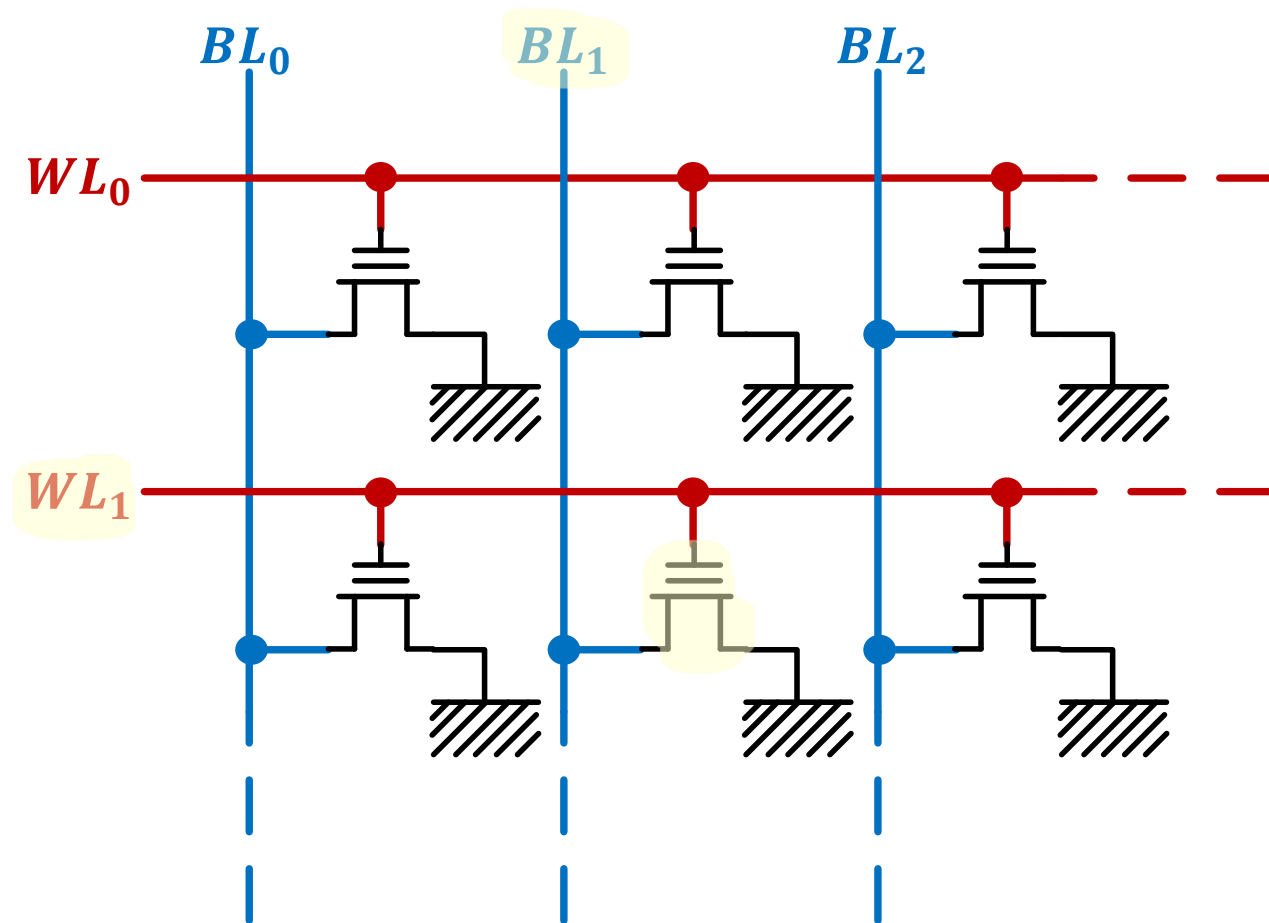
UV-EPROM (or EPROM)

- It is based on FAMOS transistor
 - In practice, it is a PROM with FAMOS transistor instead of MOS + fuse (or anti-fuse)
- Erasing procedure = exposure to UV light
 - From here the name → **UV-EPROM**
 - The chip is encapsulated in a window
 - Erasing the whole chip (ROM content) at once
- Also called just **EPROM**
 - It was the first type of EPROM



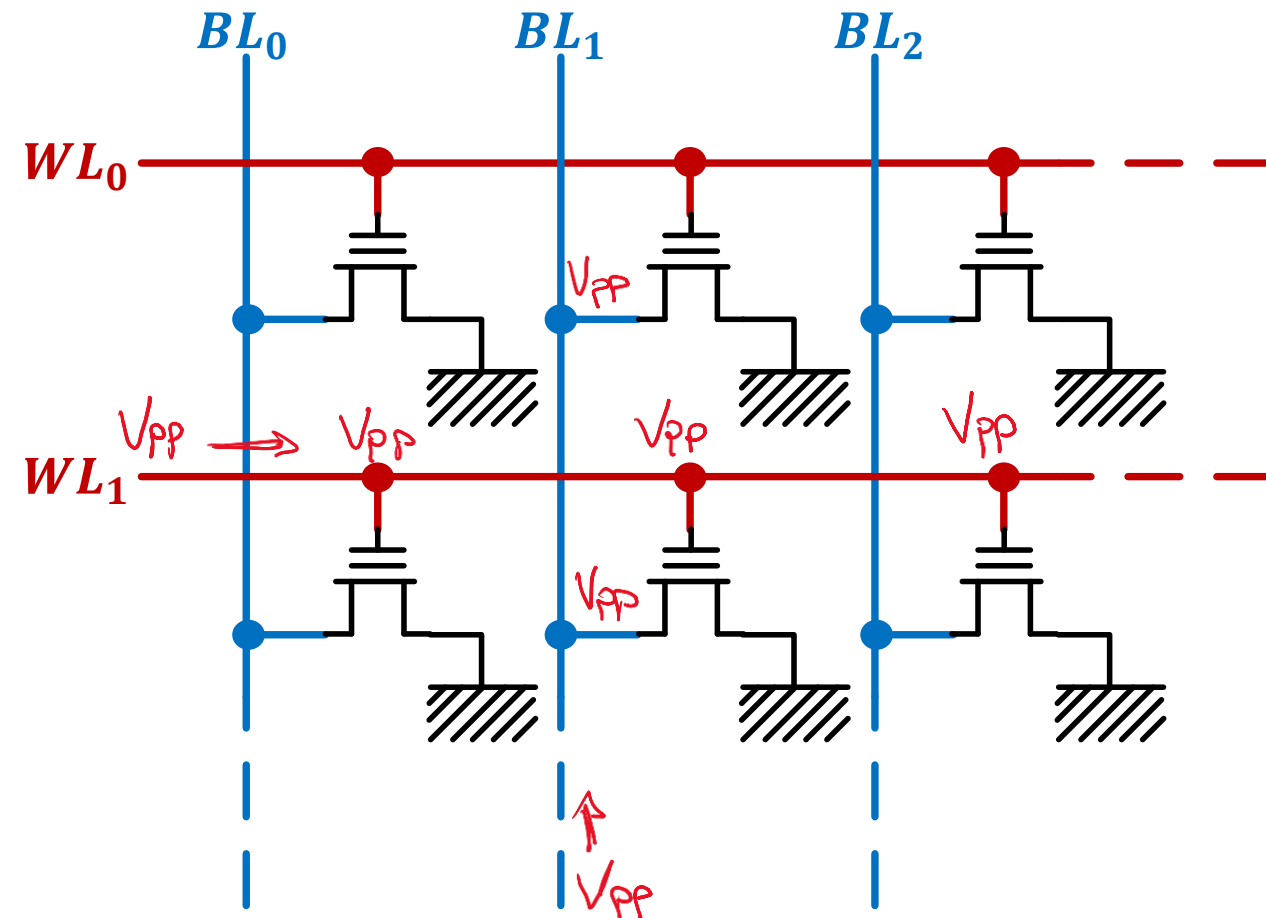
UV-EPROM (or EPROM)

- Working principle
 - Reading: the same as ROM/PROM
 - If transistor programmed → OFF
 - Otherwise (not programmed) → ON
 - Erasing: exposure to UV light
 - Programming – Example
 - Programming cell (1,1)



UV-EPROM (or EPROM)

- Working principle
 - Reading: the same as ROM/PROM
 - If transistor programmed → OFF
 - Otherwise (not programmed) → ON
 - Erasing: exposure to UV light
 - Programming – Example
 - Programming cell (1,1)
 - $V_G = WL_1 = V_{PP}$
 - $V_D = BL_1 = V_{PP}$

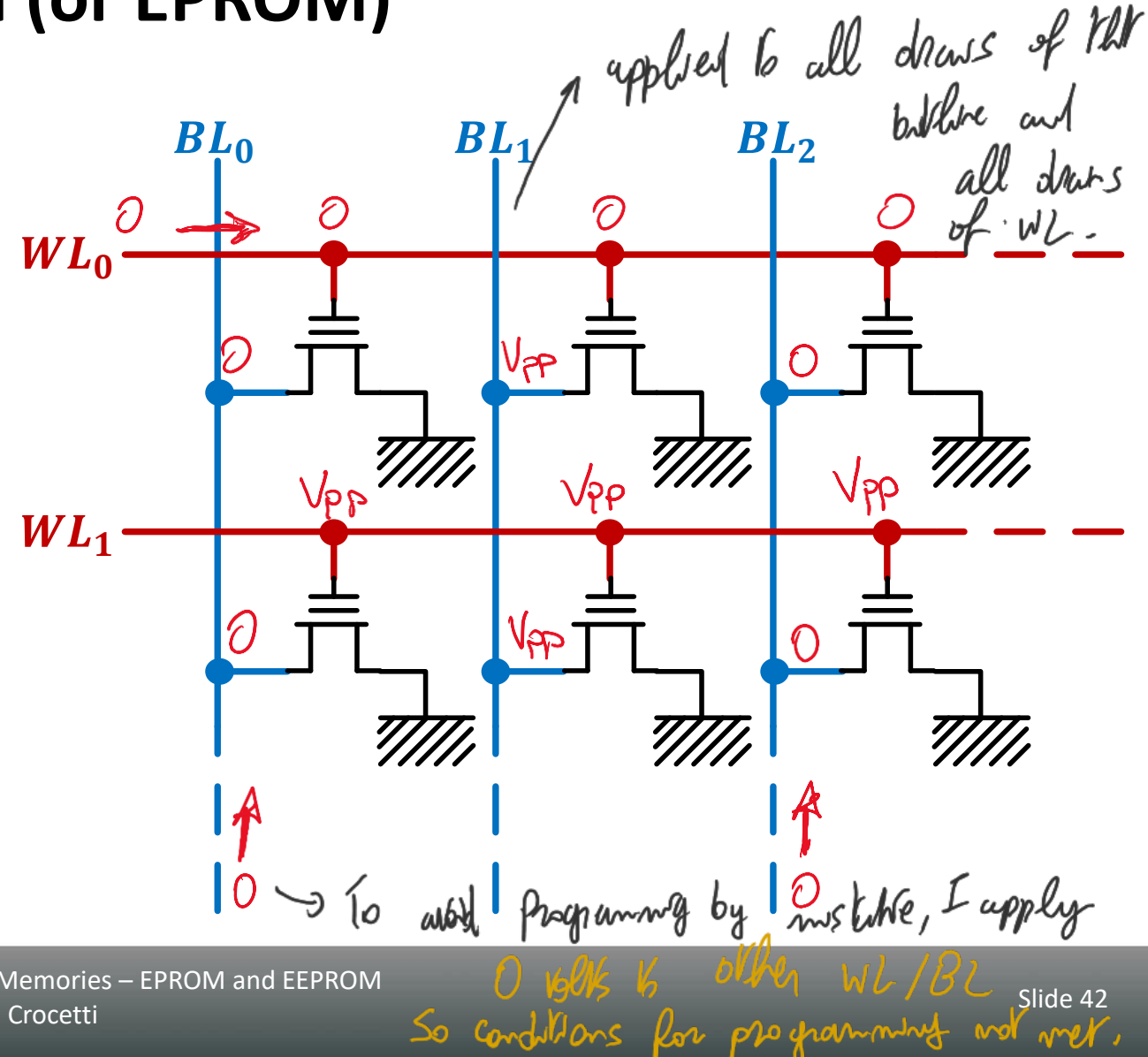


UV-EPROM (or EPROM)

• Working principle

- Reading: the same as ROM/PROM
 - If transistor programmed → OFF
 - Otherwise (not programmed) → ON
- Erasing: exposure to UV light
- Programming – Example
 - Programming cell (1,1)
 - $V_G = WL_1 = V_{PP}$
 - $V_D = BL_1 = V_{PP}$
 - All other $WL_i = 0$ and $BL_j = 0$!

$$V_{PP} \gg V_{t1} V_{DD}$$

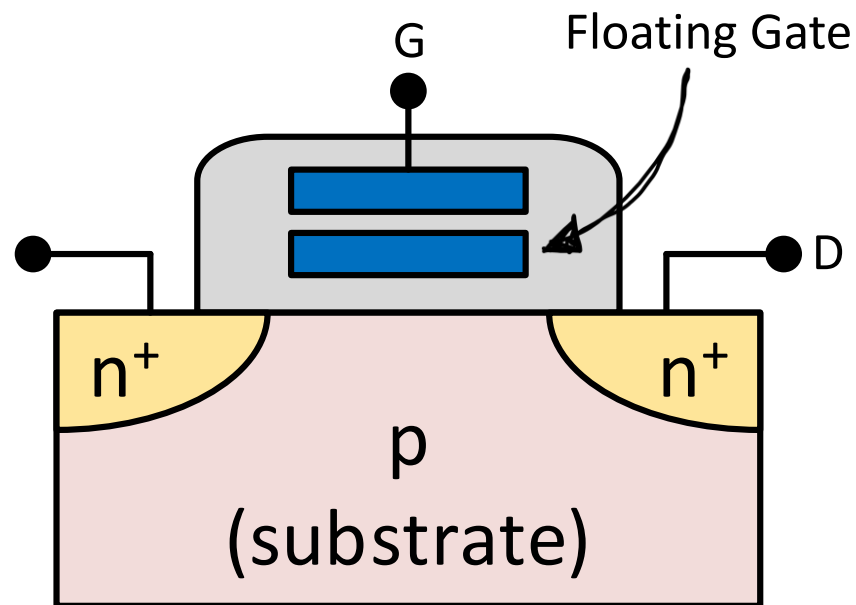


FLOTOX transistor

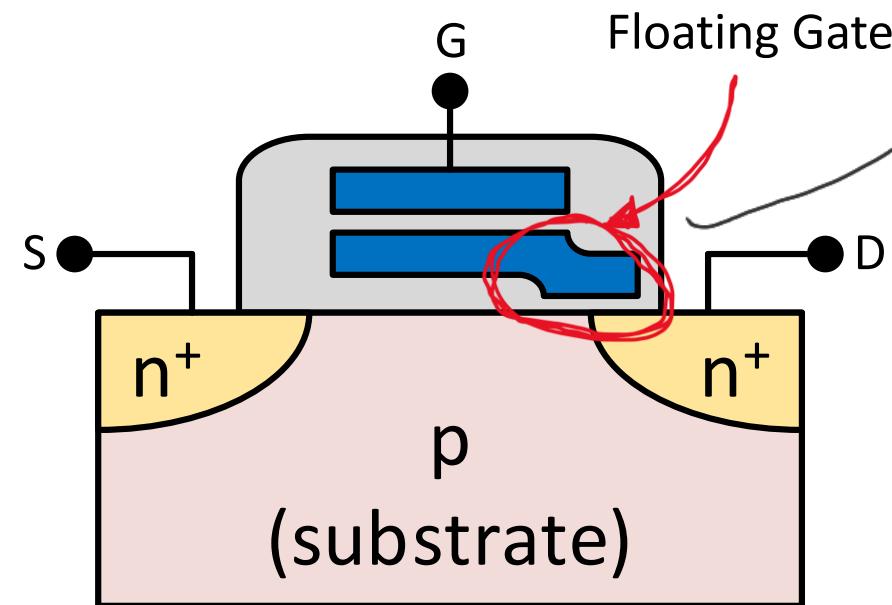
- Some differences w.r.t. FAMOS transistor
 - Floating gate extends over Drain and is separated from it by a very thin oxide layer

FLOTOX transistor

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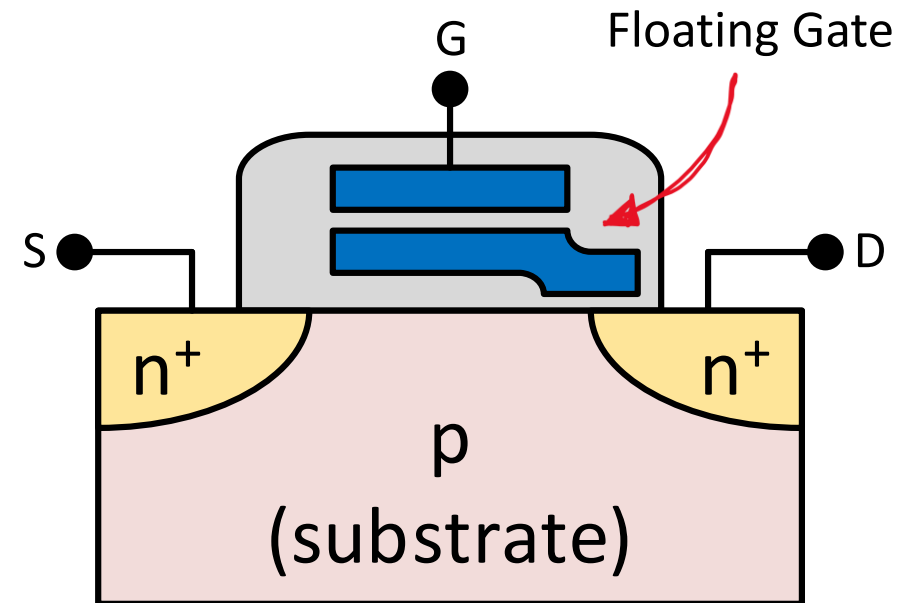
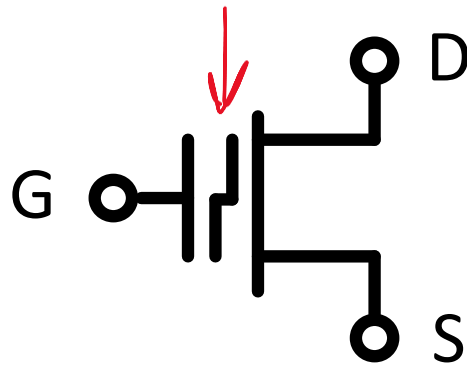
FAMOS



FLOTOX

FLOTOX transistor

- Some differences w.r.t. FAMOS transistor
 - Also the symbol is different



FLOTOX transistor

- Working principle

- Electrons injection (programming)

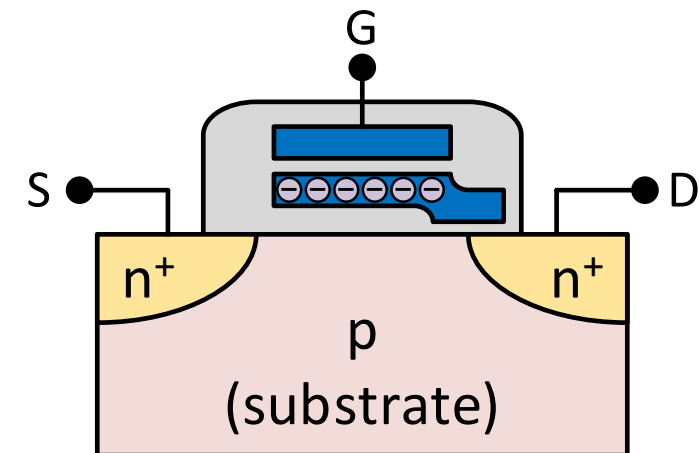
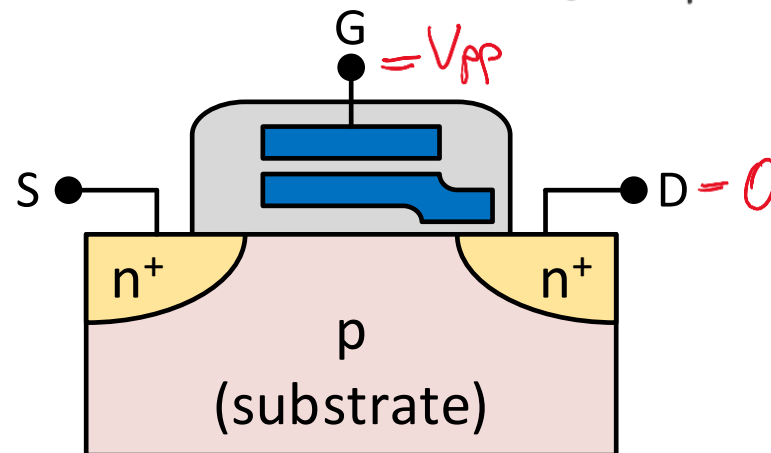
- Tunnel effect (thanks to the very thin oxide layer) → Floating-gate Tunnel-Oxide MOS

- $V_G = V_{PP}$

- $V_D = 0$

- V_S : not specified (high impedance)

Tunnel effect is the one that makes electron jump in the floating gate. No need to know more ↓



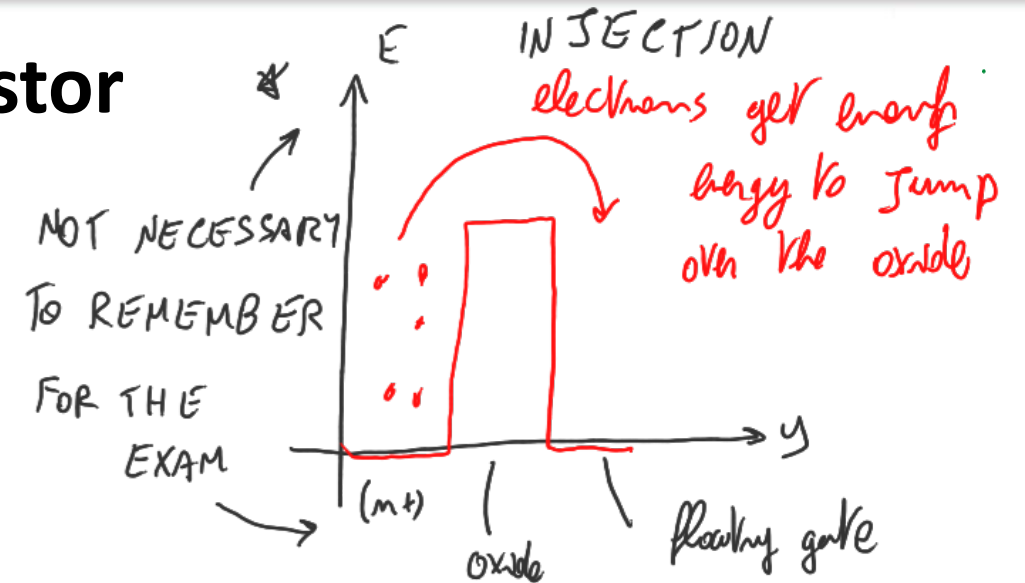
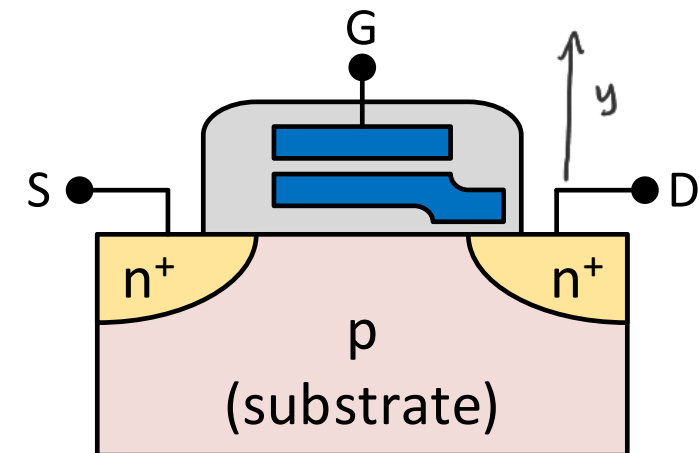
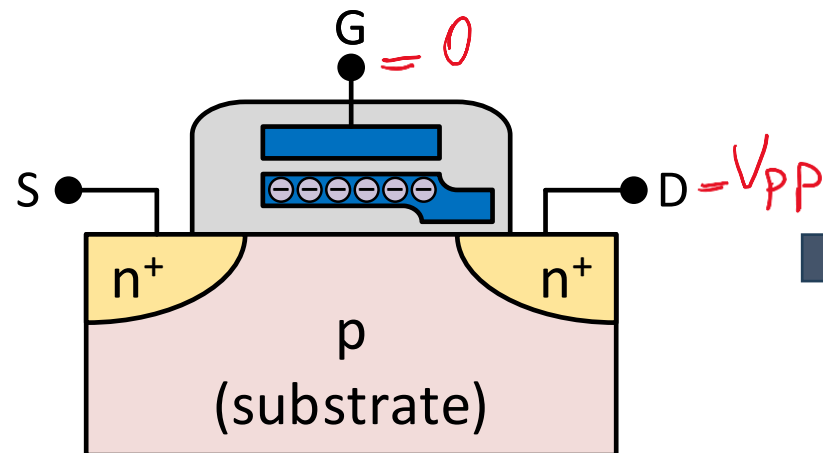
FLOTOX transistor

- Working principle

- Electrons removal (erasing)

- Tunnel effect (again)


- $V_G = 0$
 - $V_D = V_{PP}$
 - V_S : not specified (high impedance)



EEPROM (or E²PROM)

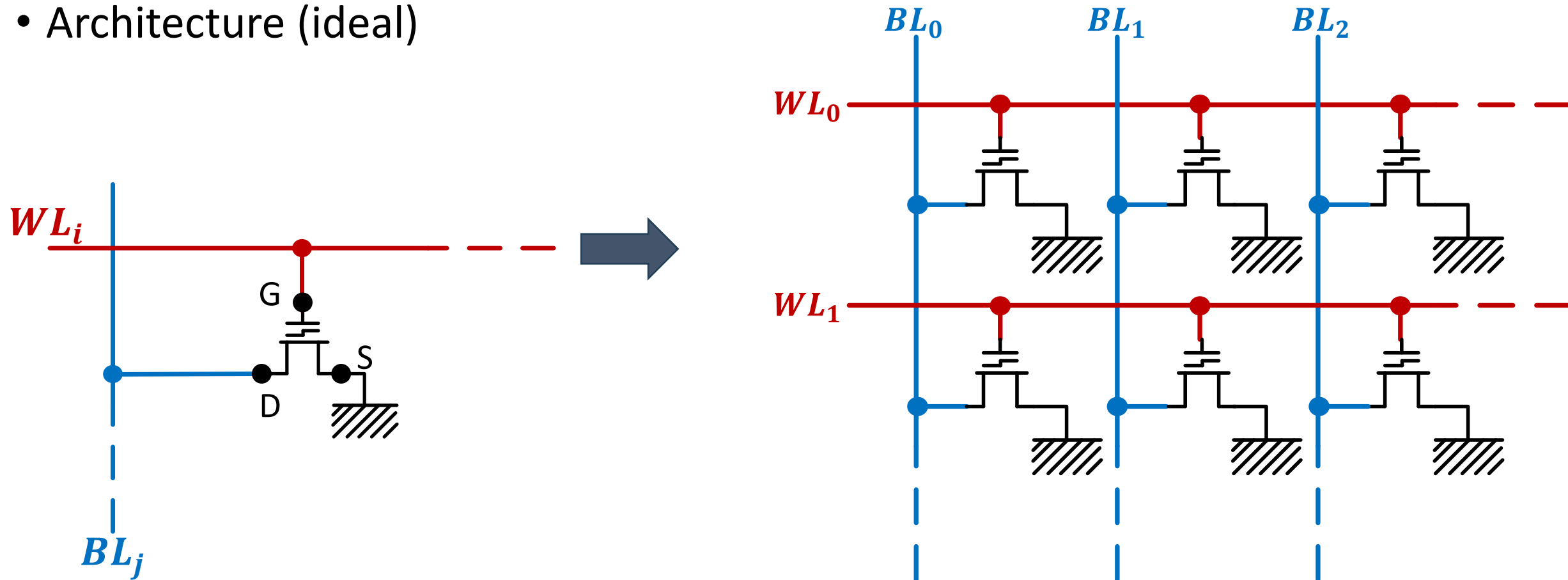
- It is based on FLOTOX transistor
 - In practice, it is a PROM with FLOTOX transistor instead of MOS + fuse (or anti-fuse)
 - Ideally !!!
 - Erasing procedure = tunnel effect due to electrical quantities
 - From here the name → EEPROM = Electrically Erasable PROM
 - Or E²PROM
 - Erasing only selected memory cells (FLOTOX transistors)

EEPROM (or E²PROM)

- It is based on FLOTOX transistor
 - In practice, it is a PROM with FLOTOX transistor instead of MOS + fuse (or anti-fuse)
 - Ideally !!!  why ideally possible to realise memory cell with one flox?
 - Erasing procedure = tunnel effect due to electrical quantities
 - From here the name → **EEPROM** = Electrically Erasable **PROM**
 - Or **E²PROM**
 - Erasing only selected memory cells (FLOTOX transistors)

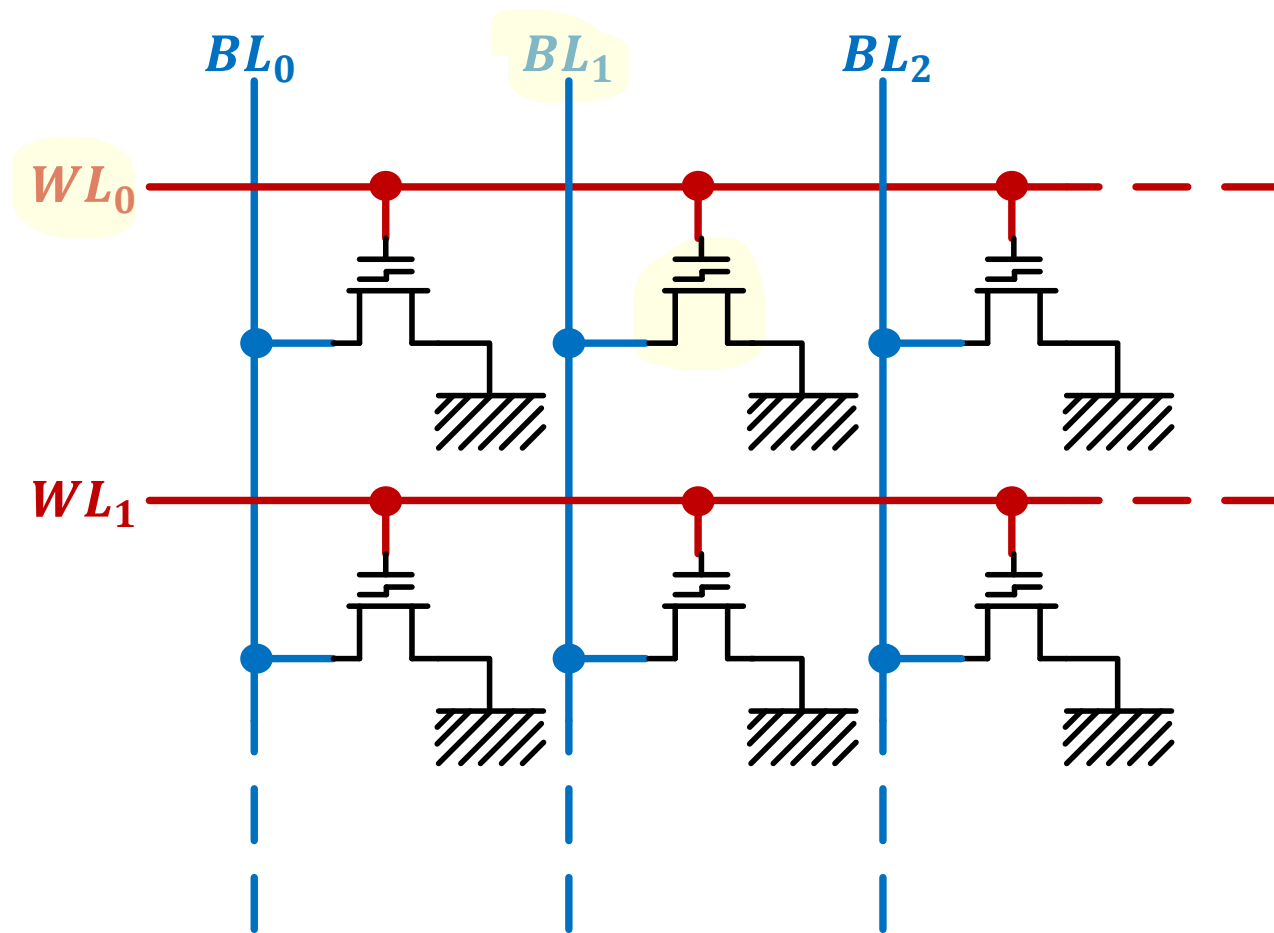
EEPROM (or E²PROM)

- Architecture (ideal)



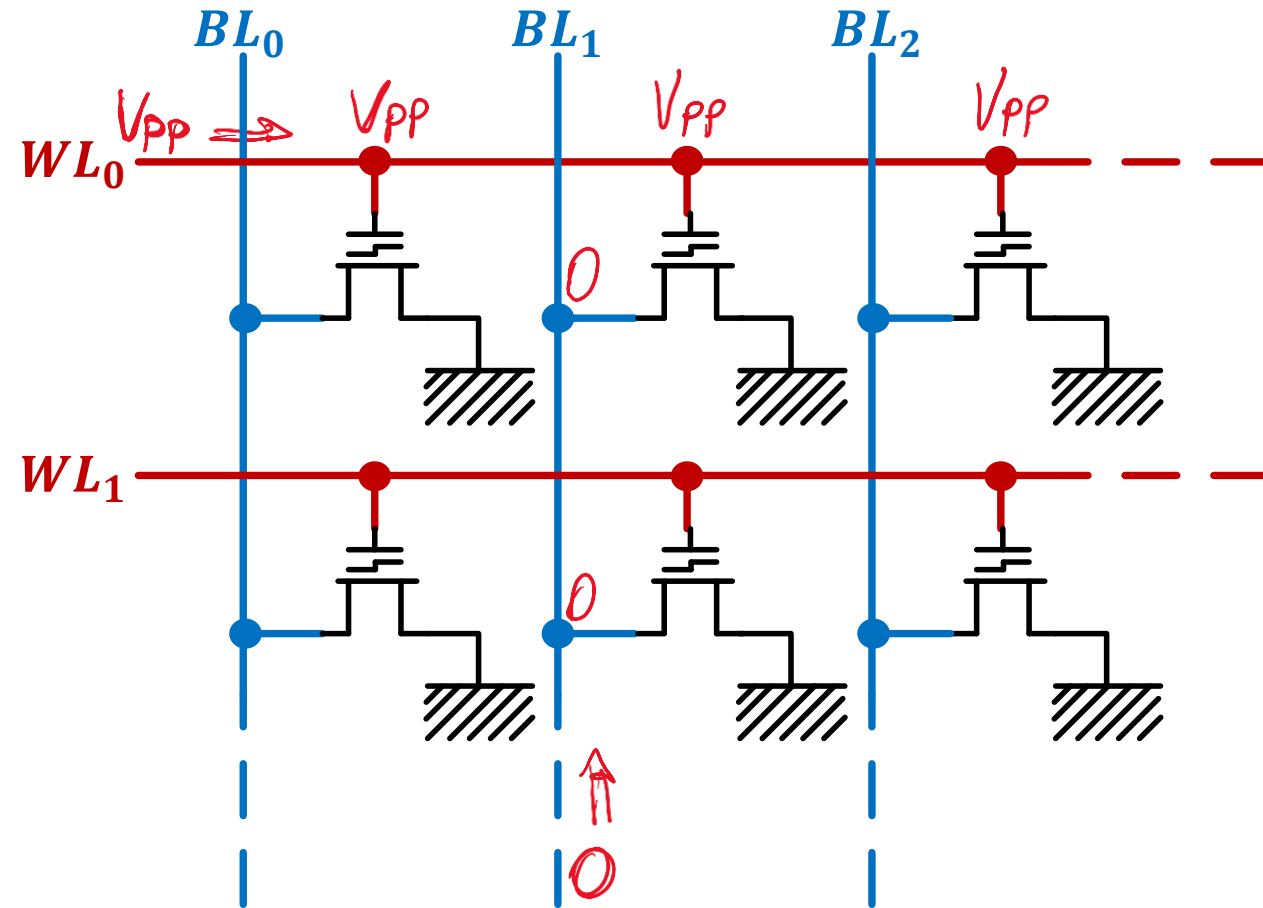
EEPROM (or E²PROM)

- Architecture (ideal)
 - Programming cell (0,1)



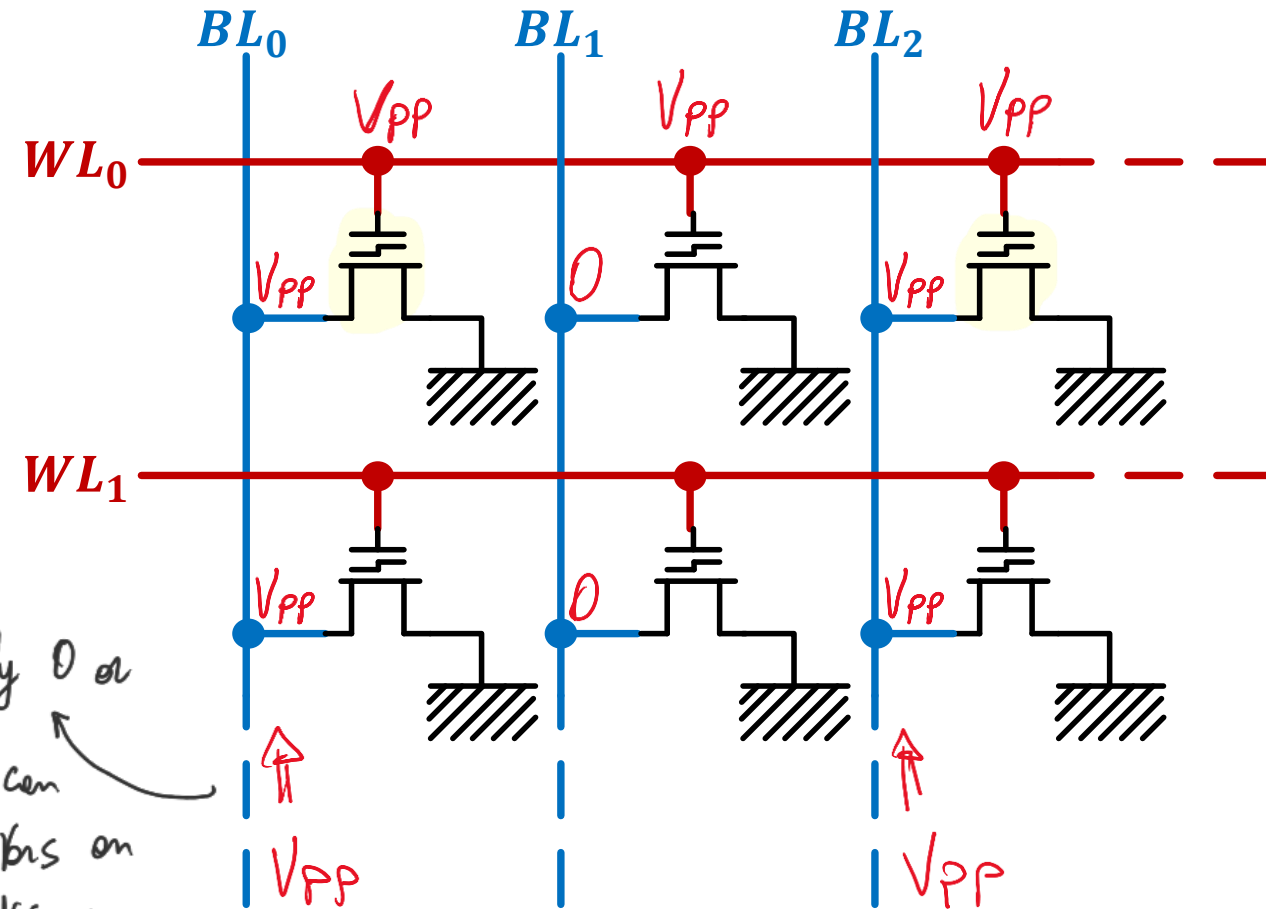
EEPROM (or E²PROM)

- Architecture (ideal)
 - Programming cell (0,1)
 - $V_G = WL_0 = V_{PP}$
 - $V_D = BL_1 = 0$



EEPROM (or E²PROM)

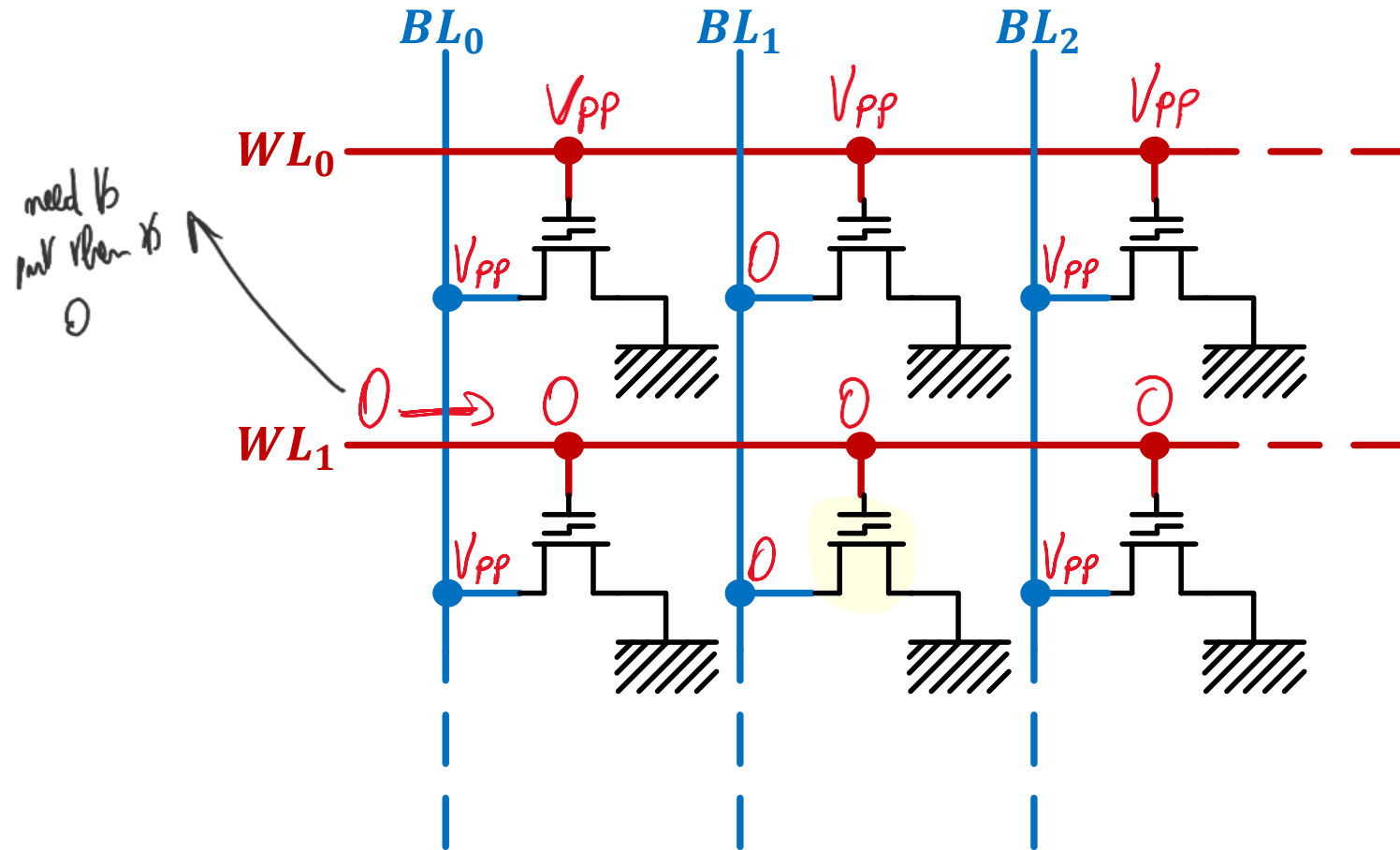
- Architecture (ideal)
 - Programming cell (0,1)
 - $V_G = WL_0 = V_{PP}$
 - $V_D = BL_1 = 0$
 - All other $BL_j = V_{PP}$
 - Otherwise the other cells in the same WL_0 are programmed !



if I apply 0 or
leave unconnected, I can
program the transistors on
other locations.

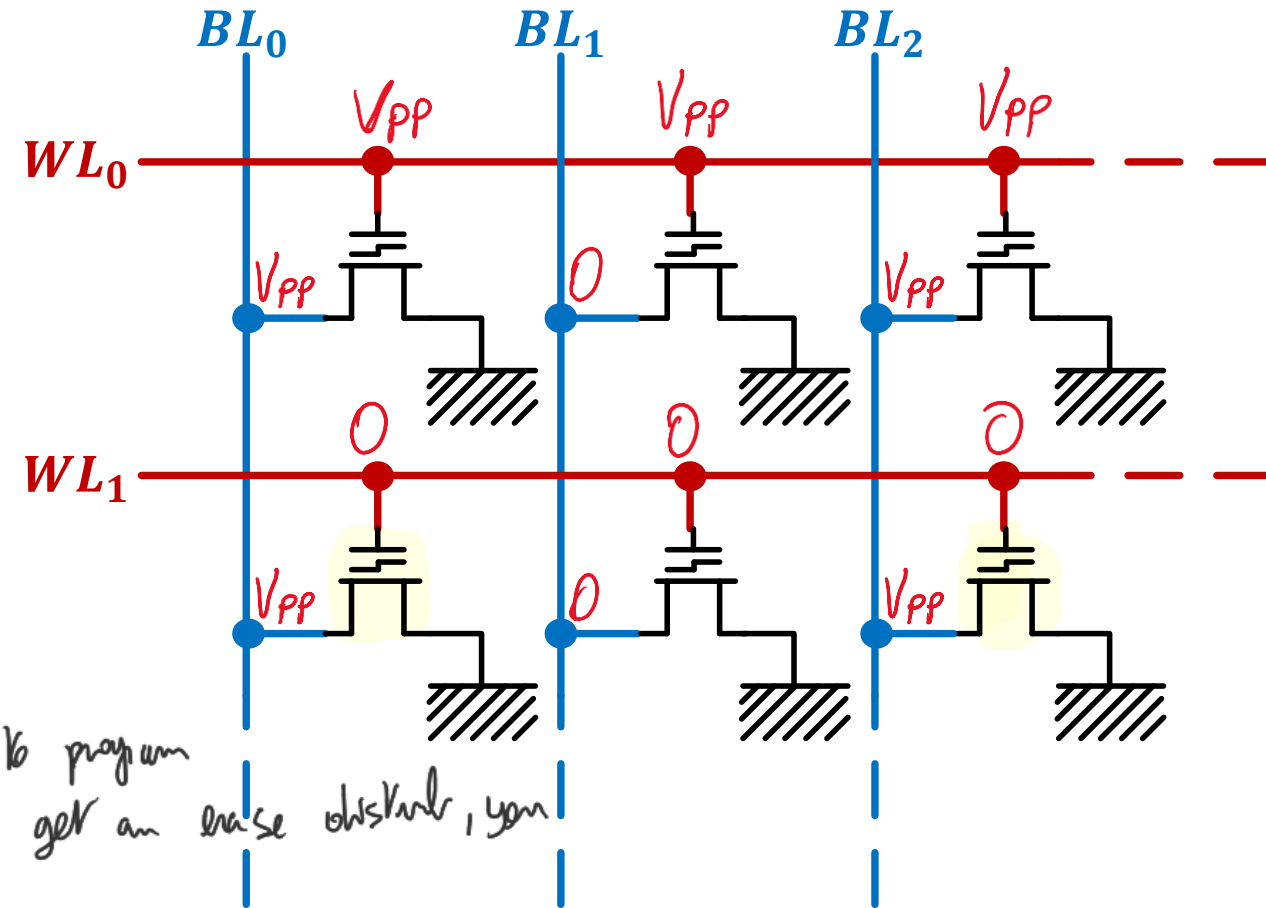
EEPROM (or E²PROM)

- Architecture (ideal)
 - Programming cell (0,1)
 - $V_G = WL_0 = V_{PP}$
 - $V_D = BL_1 = 0$
 - All other $BL_j = V_{PP}$
 - Otherwise the other cells in the same WL_0 are programmed !
 - All other $WL_i = 0$
 - Otherwise the other cells in the same BL_1 are programmed !



EEPROM (or E²PROM)

- Architecture (ideal)
 - Programming cell (0,1)
 - $V_G = WL_0 = V_{PP}$
 - $V_D = BL_1 = 0$
 - All other $BL_j = V_{PP}$
 - Otherwise the other cells in the same WL_0 are programmed !
 - All other $WL_i = 0$
 - Otherwise the other cells in the same BL_1 are programmed !



- But ... **ERASE DISTURB !!!**

when you try to program a transistor you get an erase disturb, you erase others too.

EEPROM (or E²PROM)

- Architecture (ideal)

- Similarly, **WRITE DISTURB !!!**

- Erasing cell (1,2)

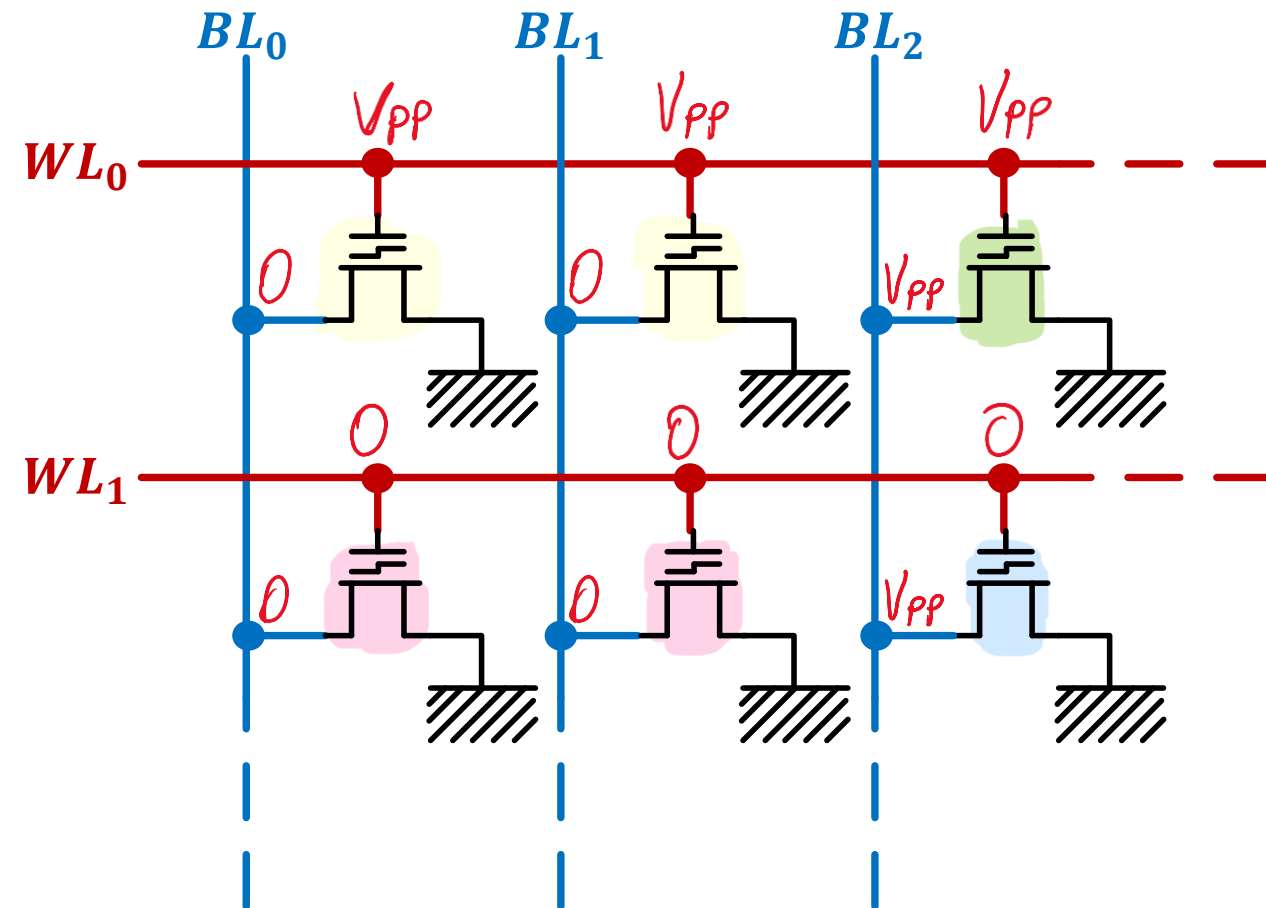
- $V_G = WL_1 = 0$
 - $V_D = BL_2 = V_{PP}$

- All other $BL_j = 0$

- Otherwise the other cells in the same WL_1 are erased !

- All other $WL_i = V_{PP}$

- Otherwise the other cells in the same BL_2 are erased !

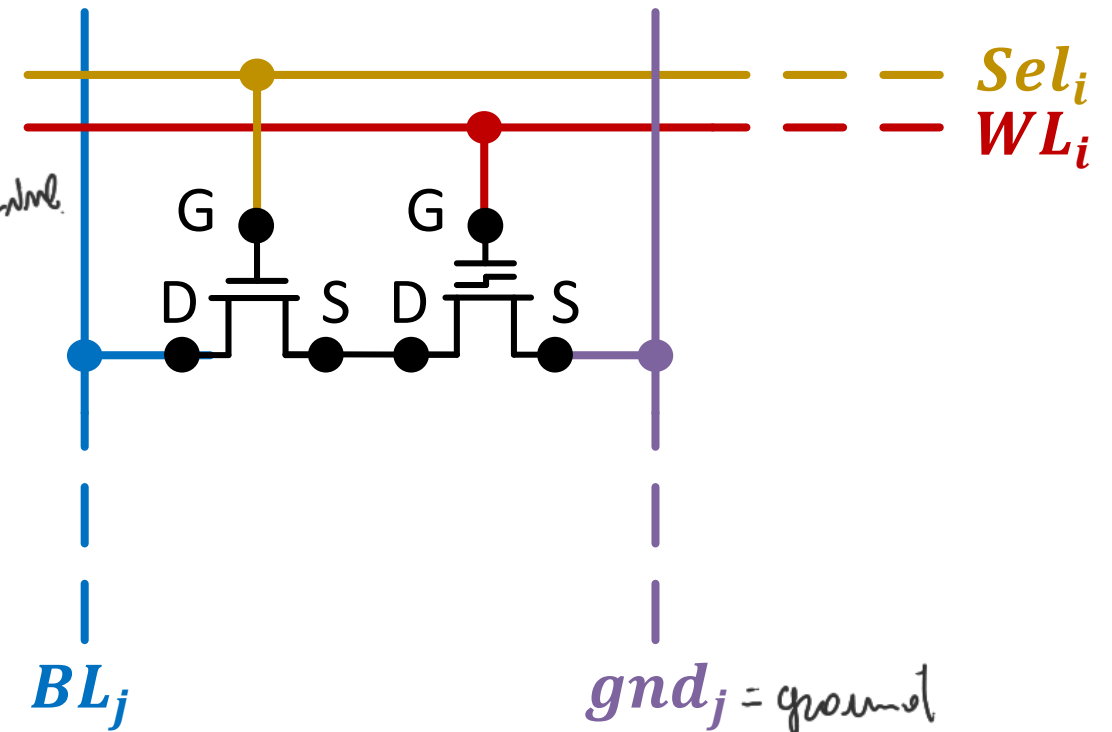


EEPROM (or E²PROM)

- Architecture (real) – To solve the problems

- Memory cell

- 2 transistors → switch to connect or disconnect a memory from the bitline.
- 1x FLOTOX
- 1x n-MOS (pass transistor)



EEPROM (or E²PROM)

- Architecture (real) – To solve the problems
 - How should be driven

Just for the sake of completeness

- It won't be part of the exam!!

Operation	WL_i	Sel_i	BL_j	gnd_j	$WL_{i'}$	$Sel_{i'}$	$BL_{j'}$	$gnd_{j'}$
Program (WL_i, BL_j)	V_{CC}	V_{CC}	0	Z	0	0	V_{PP}	Z
Erase (WL_i, BL_j)	0	V_{CC}	V_{PP}	Z	V_{PP}	0	0	Z
Read (WL_i, BL_j)	V_{CC}	V_{CC}	Q	0	0	0	--	0

■ Notes

- $WL_{i'}$, $Sel_{i'}$, $BL_{j'}$, and $gnd_{j'}$ indicate, respectively, all other WL , Sel , BL , and gnd different from WL_i , Sel_i , BL_j , and gnd_j
- Z = high impedance



Thank you for your attention

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